

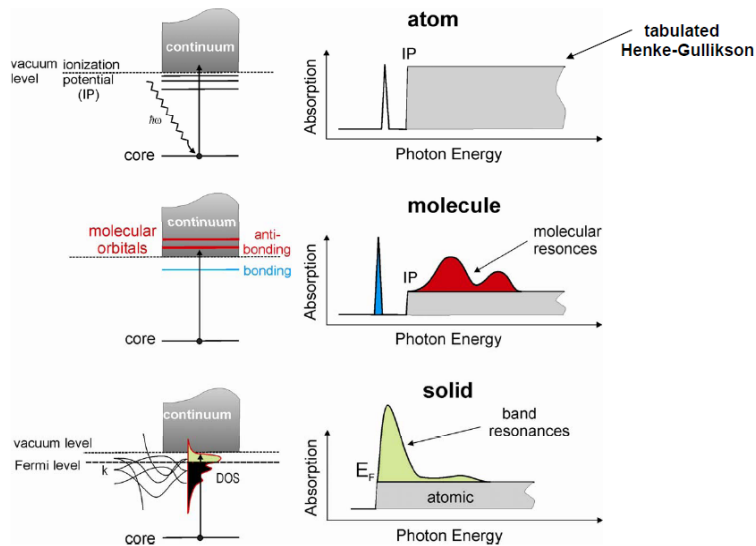
Di, 30.03.2010 X-ray Absorption Spectroscopy (F. Nolting)

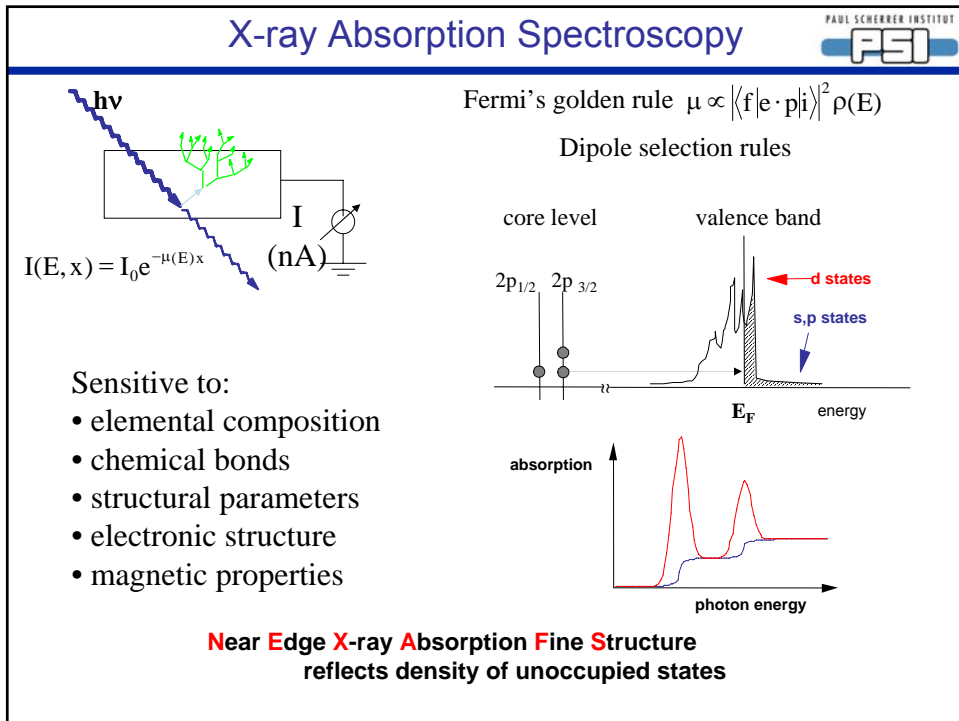
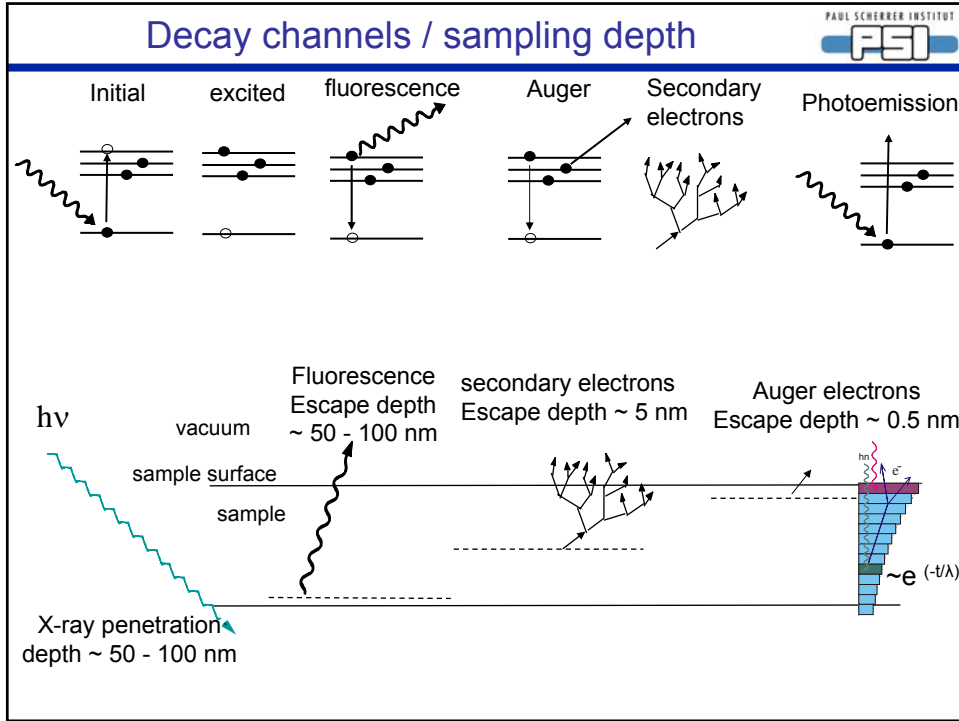
Di, 06.04.2010 X-ray Microscopy (F. Nolting)

Both with an emphasis of magnetism

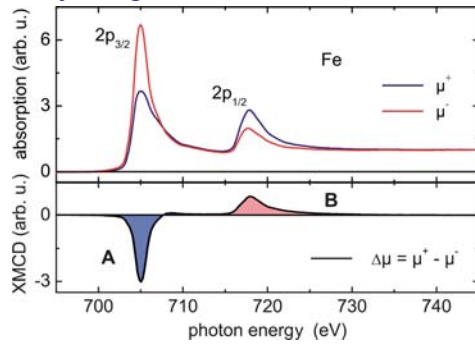
- Repetition Spectroscopy
- Crash course nanomagnetism
- Introduction
- Photoemission electron microscope (PEEM)
 - Technique
 - Nanocrystals
 - Heterostructure/Magnetisation dynamics
- Transmission X-ray microscope (Scanning: STXM/ full field: TXM)
- Combine X-rays with scanning probe microscopy
- PEEM without X-rays

X-ray Absorption Spectra in a Nutshell





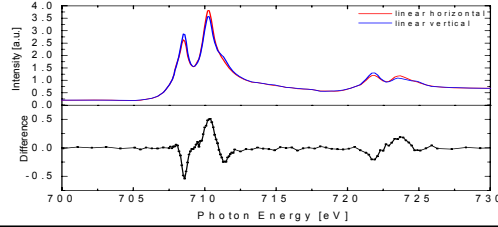
X-ray Magnetic Circular Dichroism (XMCD)



$$\text{XMCD} \sim \mathbf{M} \cos(\mathbf{M}, \mathbf{S})$$

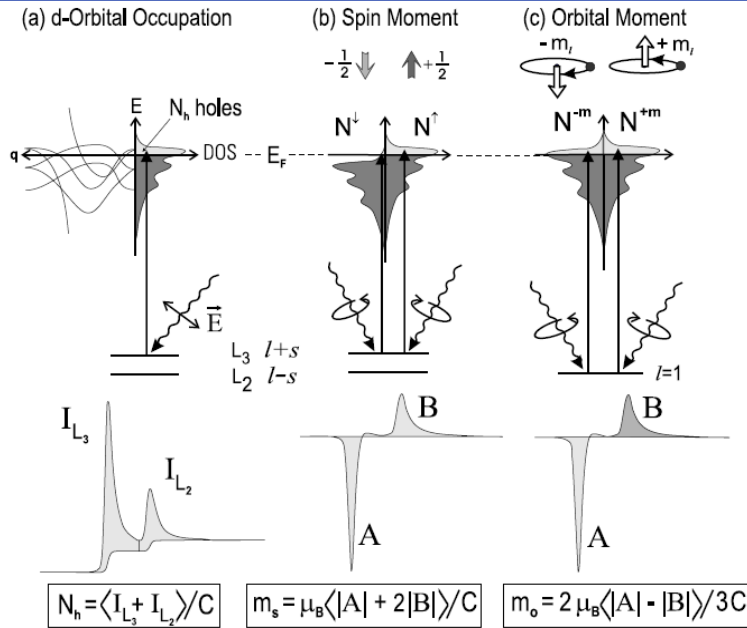
Spin and Orbital moment
Element resolved hysteresis
Look at interfaces
Look at small effects

X-ray Magnetic Linear Dichroism (XMLD)



$$\text{XMLD} \sim \langle \mathbf{M}^2 \rangle$$

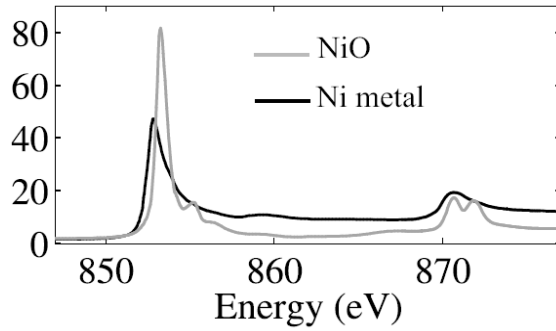
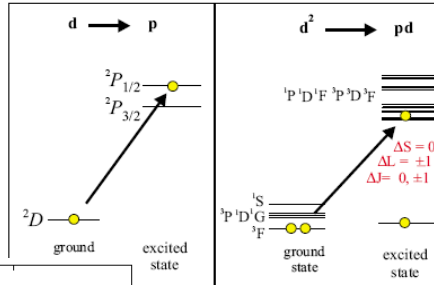
Sum rules



Ni metal vs NiO

Ni metal: Ni¹⁺, d⁹

NiO: Ni²⁺, d⁸

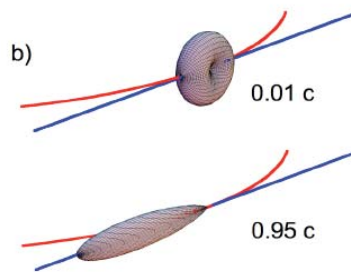
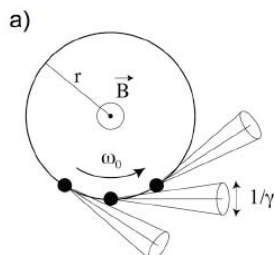


Creation of electromagnetic radiation

The Liénard–Wiechert field $E(t)$ of a point charge q detected by an observer at a time t is determined by the distance r^* , the velocity v^* , and acceleration a^* of the charge at the emission or retarded time $t^* = t - r^*/c$. Defining $\beta^* = v^*/c$ we have

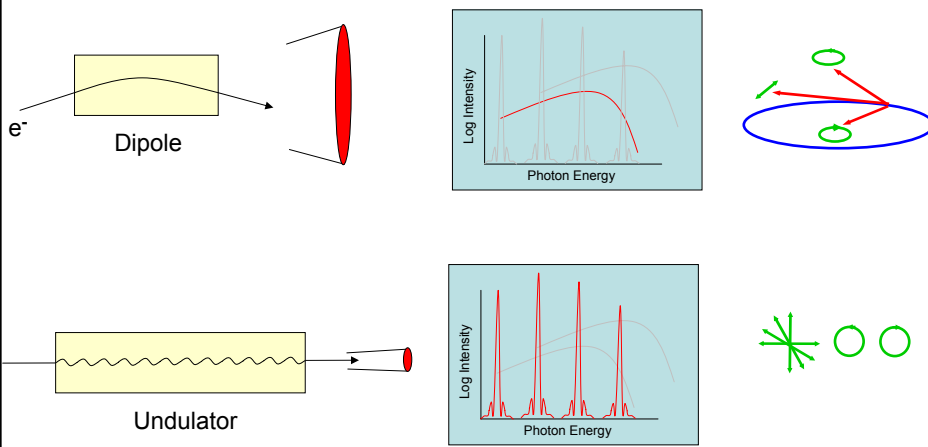
$$E(t) = \frac{q}{4\pi\epsilon_0} \underbrace{\frac{1 - (\beta^*)^2}{(r^*)^2 (1 - n^* \cdot \beta^*)^3} [n^* - \beta^*]}_{\text{velocity field}} + \frac{q}{4\pi\epsilon_0} \underbrace{\frac{1}{c^2 r^* (1 - n^* \cdot \beta^*)^3} \{n^* \times [(n^* - \beta^*) \times a^*]\}}_{\text{acceleration field}} \quad (4.58)$$

We have indicated all retarded quantities by an asterisk.



polarized X-rays!

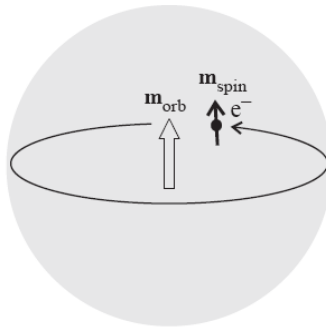
Slide Courtesy: Thomas Schmidt



Outline

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Magnetic moment

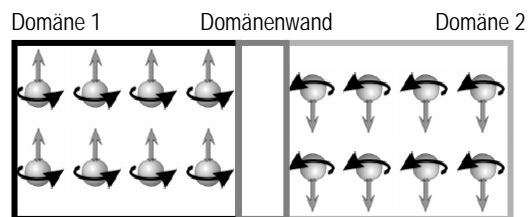


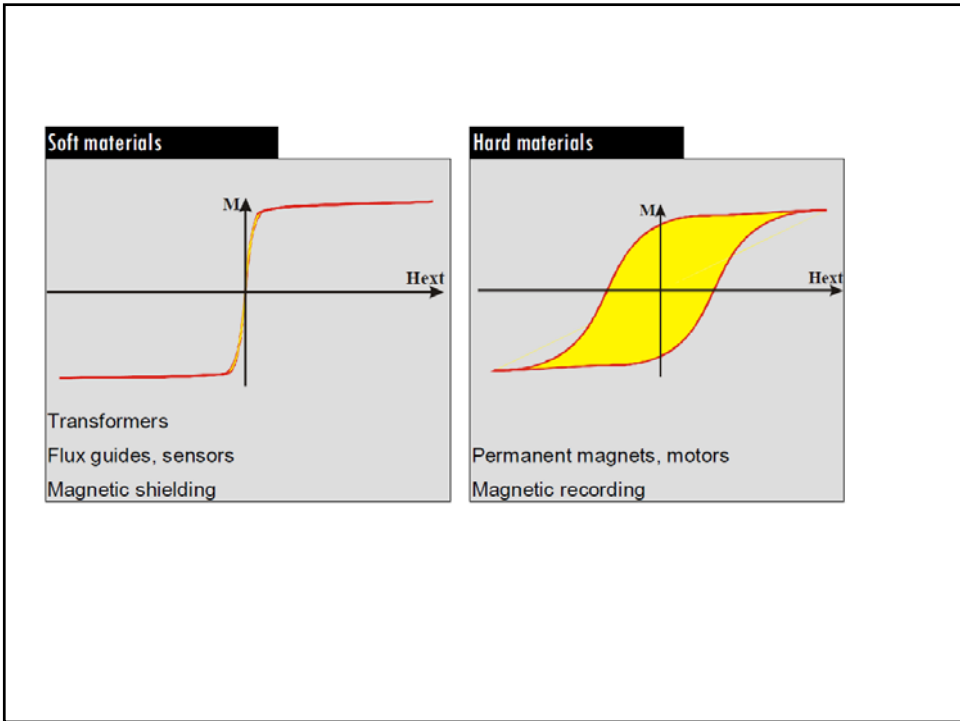
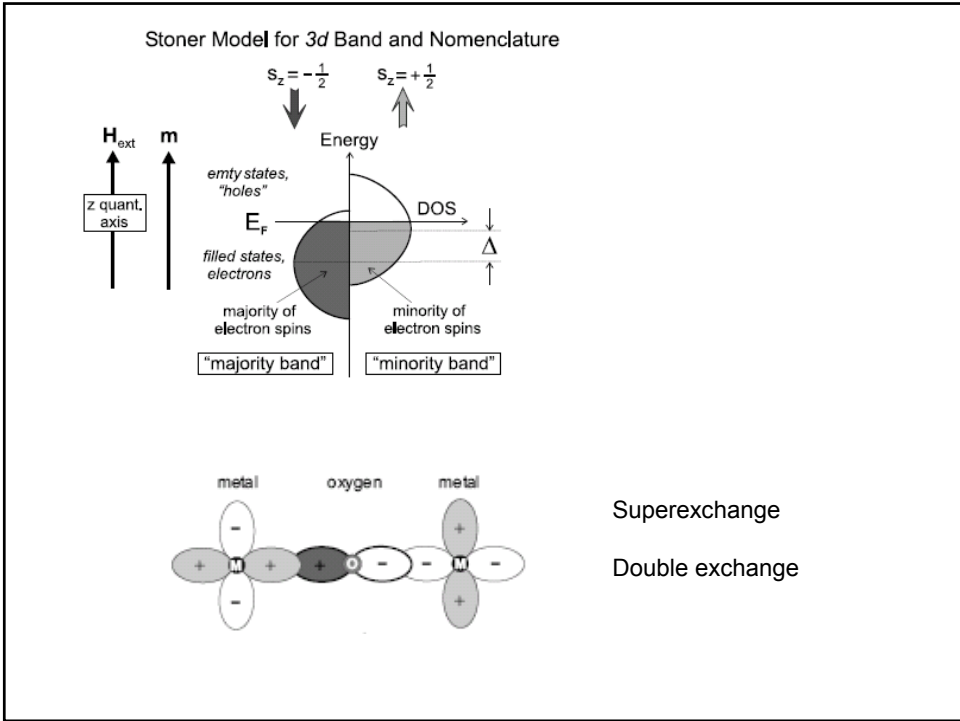
Spin moment $\sim 1.5 \mu_B / \text{atom}$ isotropic

Orbital moment $\sim 0.1 \mu_B / \text{atom}$ isotropic/anisotropic

They interact via the spin-orbit coupling $L \cdot S$

Ordering, e.g. ferromagnetismus





Domains - Energy Minimization



REVIEWS OF MODERN PHYSICS

VOLUME 21, NUMBER 4

OCTOBER, 1949

Physical Theory of Ferromagnetic Domains

CHARLES KITTEL
Bell Telephone Laboratories, Murray Hill, New Jersey

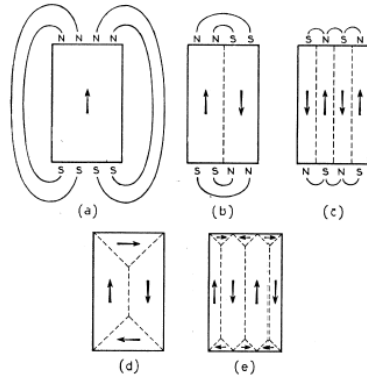


FIG. 9. The origin of domains.

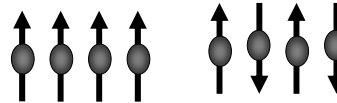
- 1907 Weiss
- 1931 Sixtus and Tonks
- 1932 Bitter
- 1935 Landau and Lifshitz

- Reviews
- C. Kittel Rev. Mod. Phys 21 (1949) 541
 - A. Hubert and R. Schäfer "Magnetic Domains" (Berlin: Springer) 1998

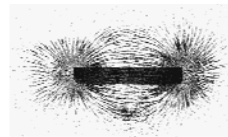
Domains - Energy Minimization



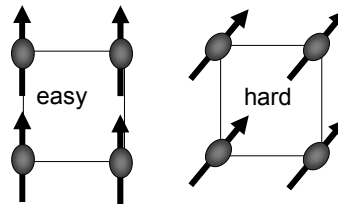
Exchange energy:
ferromagnet parallel spins
antiferromagnet antiparallel spins



Magnetostatic energy
Closure



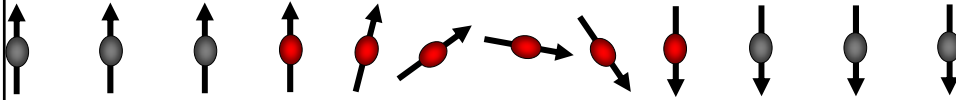
Magnetic Anisotropy
preferential magnetization along axes
easy / hard axis



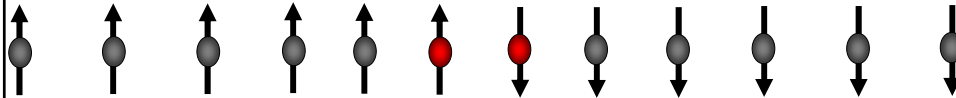
Zeeman :
spin alignment in the external magnetic field

Domain Walls

Exchange energy favors wide walls:



Anisotropy energy favors narrow walls:



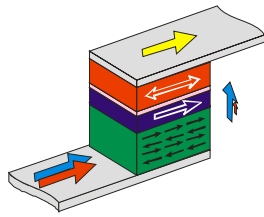
Domain wall width

$$\lambda \sim a \left(\frac{E_{\text{exchange}}}{E_{\text{anisotropy}}} \right)^{1/2}$$



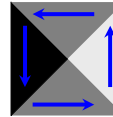
<http://perso.neel.cnrs.fr/olivier.fruchart/>

one dimension below critical length scale

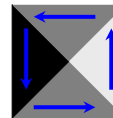


Domain size, domain wall width, Exchange length
Spin diffusion length, Spin precession length

Effect of shape



Effect of size



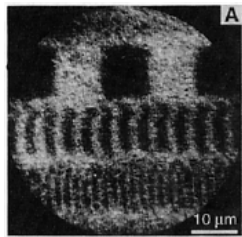
Effect of composition, coupling ...

Dealing with multielements, ferromagnetic, antiferromagnetic

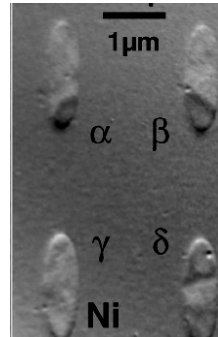
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How far did we get?

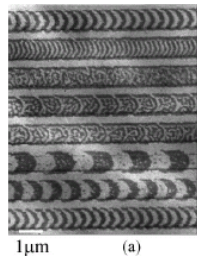


About x 50



J. Stohr, Y. Wu, B. D. Hermsmeier, M. G. Samant,
G. R. Harp, S. Koranda, D. Dunham, B. P. Tonner,
Science 259, 660 (1993)

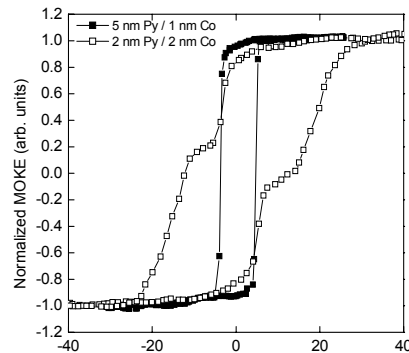
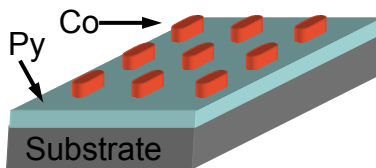
M. Hehn, D. Lacour, F. Montaigne, J.
Briones, R. Belkhou, S. El Moussaoui, F.
Maccherozzi, N. Rougemaille,
APL 92, 072501 (2008)



P. Fischer, T. Eimüller, G. Schütz et al.: *Rev. Sci.
Instrum.* **72**, 2322 (2001)

Why do we care?

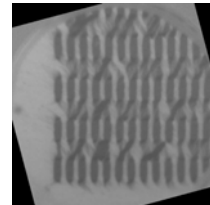
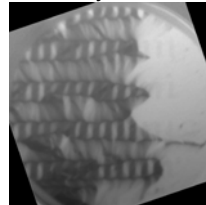
It's the function



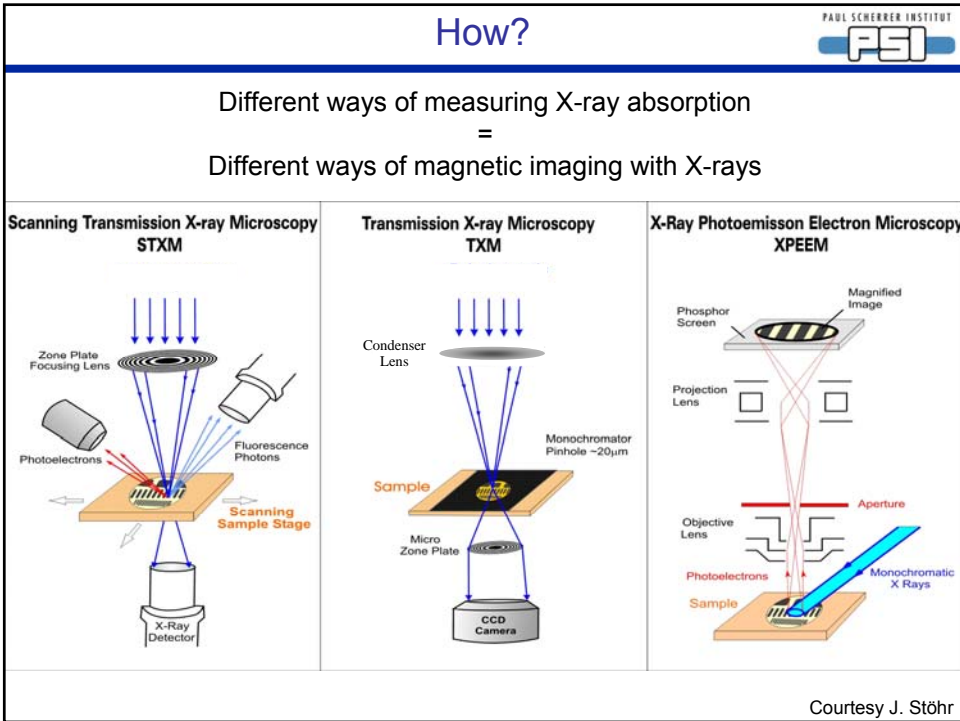
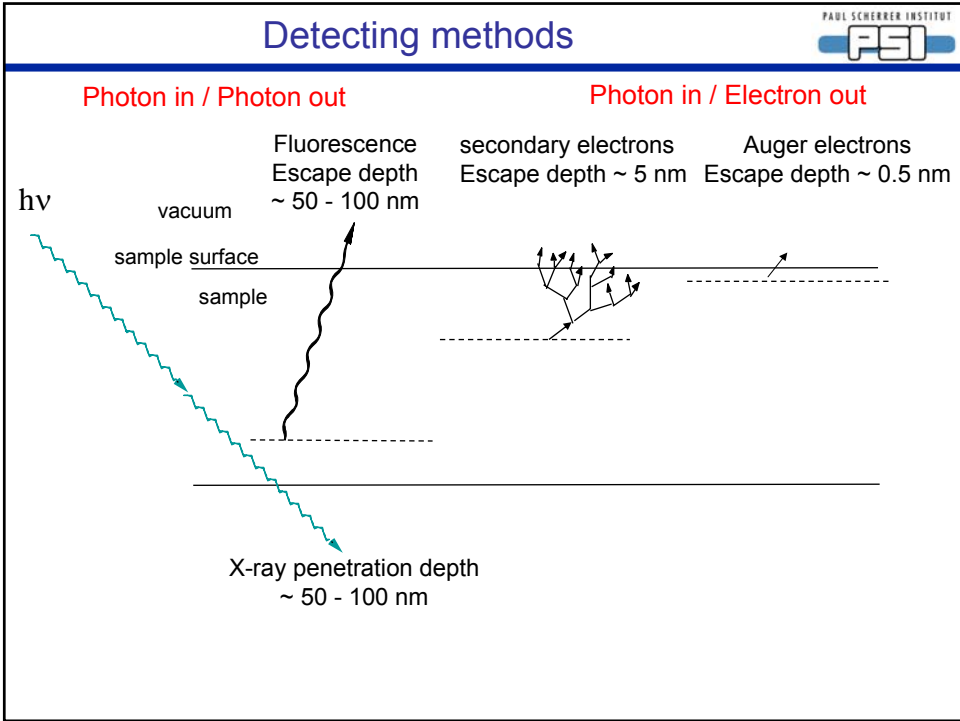
Magnetic domain
configuration in
the Py film

■ 5 nm Py / 1 nm Co □ 2 nm Py / 2 nm Co

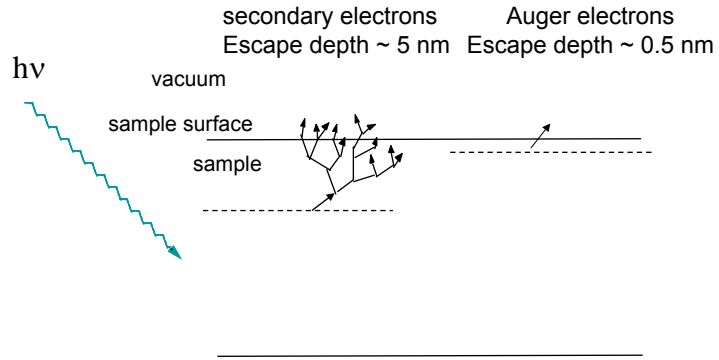
10 μm



A. Fraile Rodríguez, L. J. Heyderman, F.
Nolting, A. Hoffmann, J. E. Pearson, L.
M. Doeswijk, M. A. F. van den Boogaart,
and J. Brugger, *Appl. Phys. Lett.* **89**,
142508 (2006).

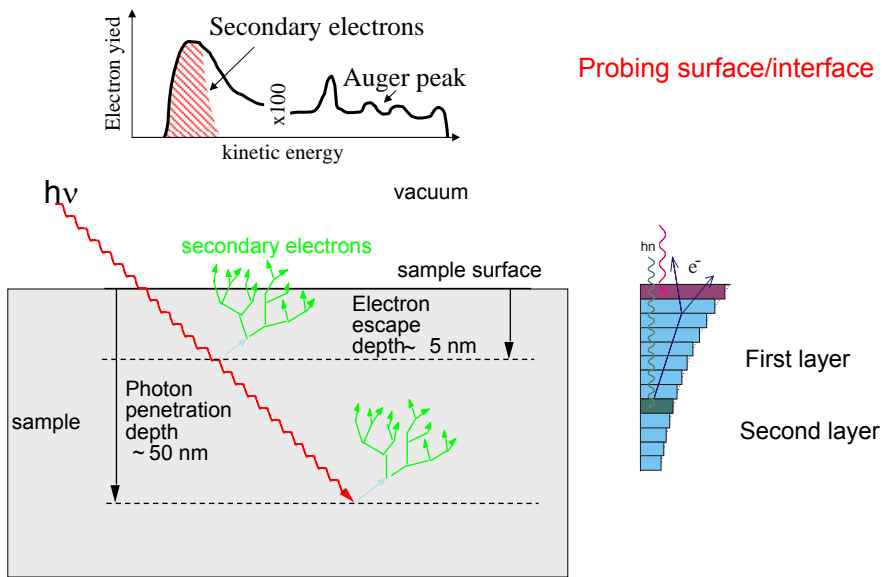


Photon in / Electron out



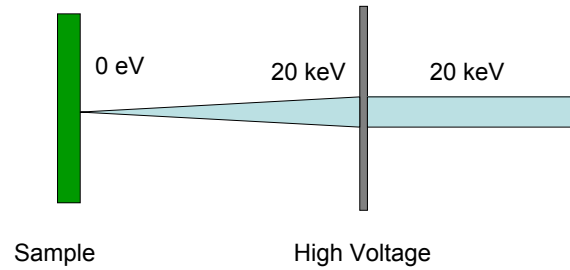
You need an optic for the electrons

This is good!



Slow Electrons

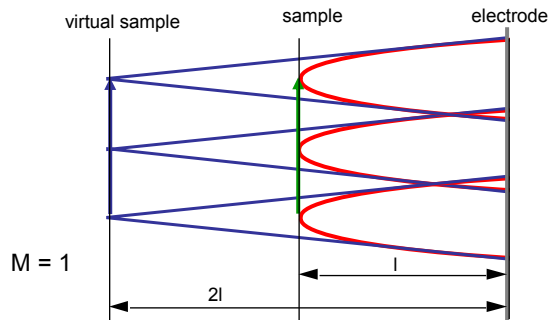
Probe : slow electrons
 Imaging : high energy electrons
 (more stable and maintain spatial information)



Immersion lens: electrons have before and after the lens different velocity (different wavelength)

Cathode lens: Sample is cathode
 electron microscope is anode

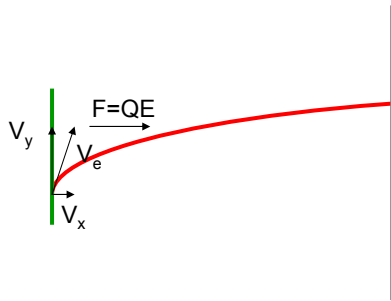
Why is the accelerating field a lens?



Accelerated electrons form parabolic trajectory
 Tangents to parabolas are the incident rays
 Extrapolated backwards form a virtual image
 at unit lateral magnification

Just another lens?

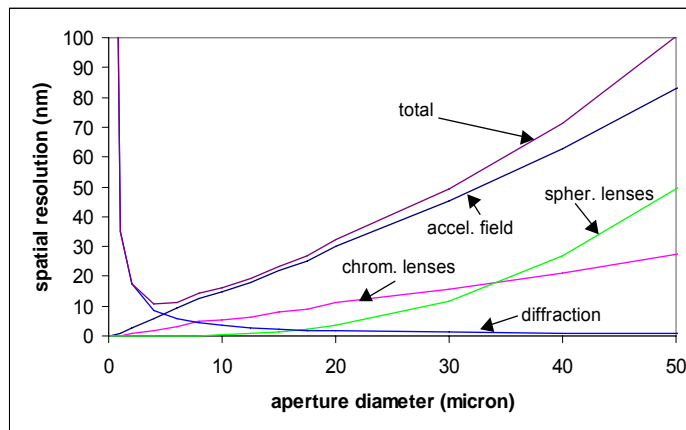
Classical: electron in homogenous electric field
calculate electron trajectory



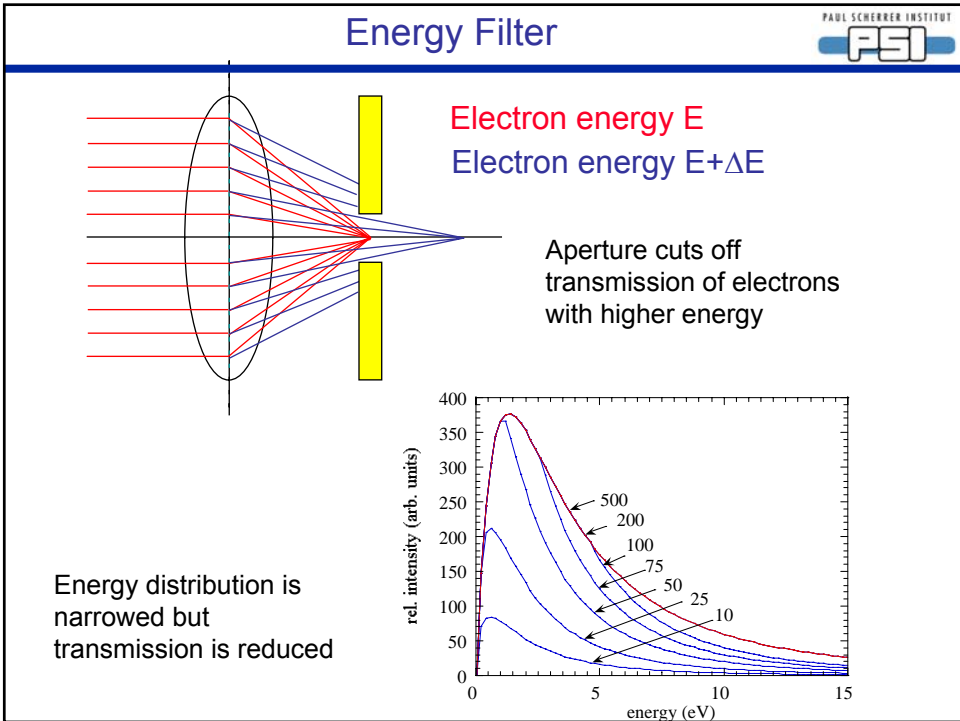
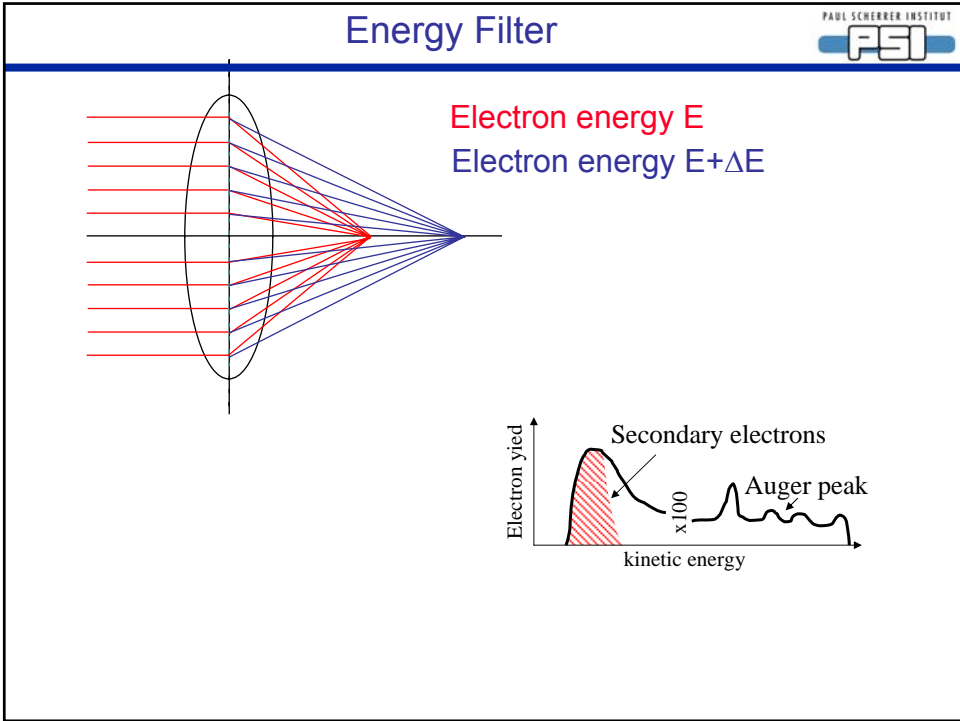
Trajectory depends on emission angle and velocity

No, it is a very important lens in a PEEM, dominating the spatial resolution due to its spherical and chromatic aberrations.

Calculated Spatial Resolution

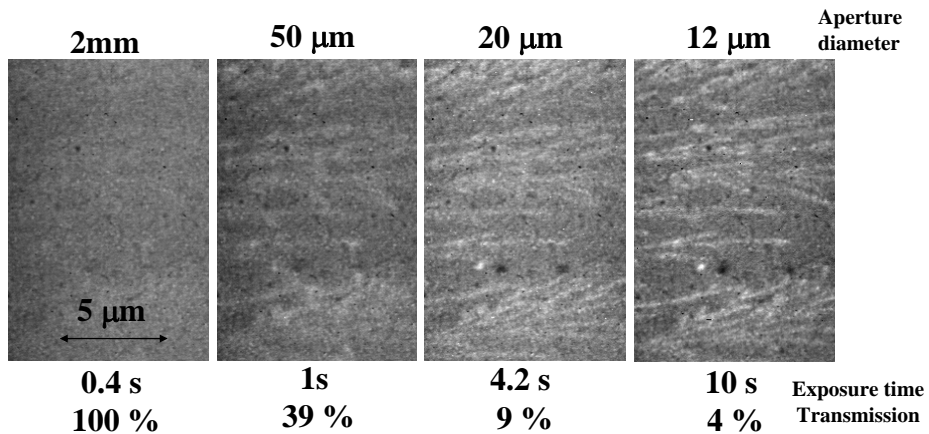


PEEM 2 at the ALS, Simone Anders
Work function 4 eV, sample voltage 30 kV, X-rays



Effect of Aperture Size on Resolution

- Spatial resolution depends on aperture size - limits pencil angle of transmitted electrons and transmission
- Highest resolution is achieved with 12 μm aperture for PEEM2, ALS



Photoemission Electron Microscopy using X-Rays

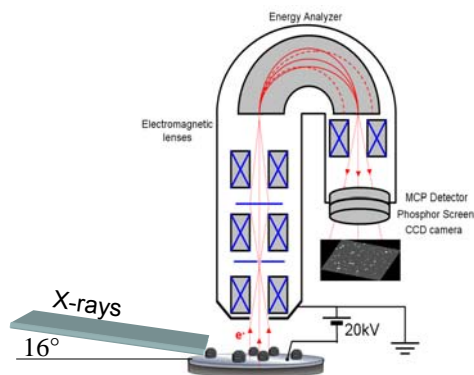
Spatially resolved X-ray absorption spectroscopy

Sensitive to:

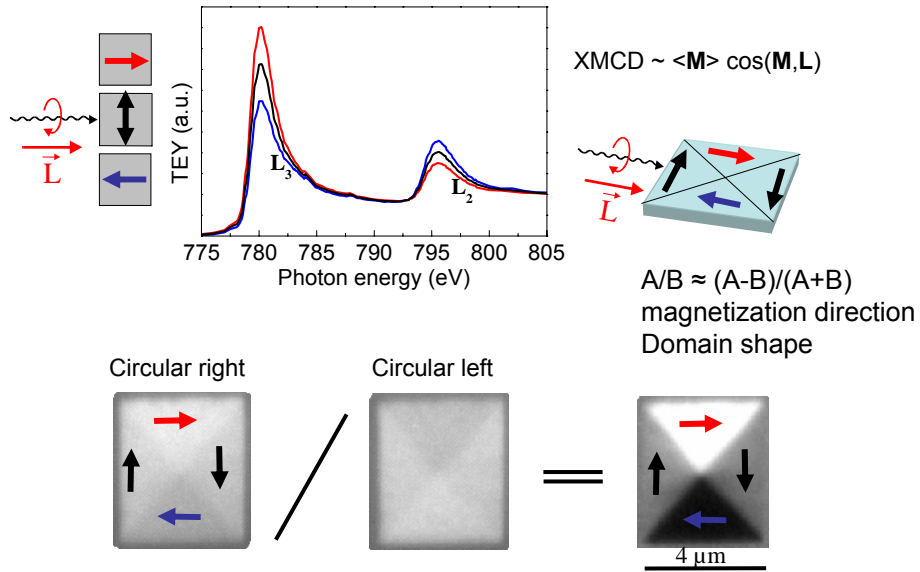
- elemental composition
- chemical bonds
- structural parameters
- electronic structure
- magnetic properties

SIM beamline at the SLS
Energy range 100 – 2000 eV
Circular and linear polarization

Schematic layout of the PEEM (ELMITEC)

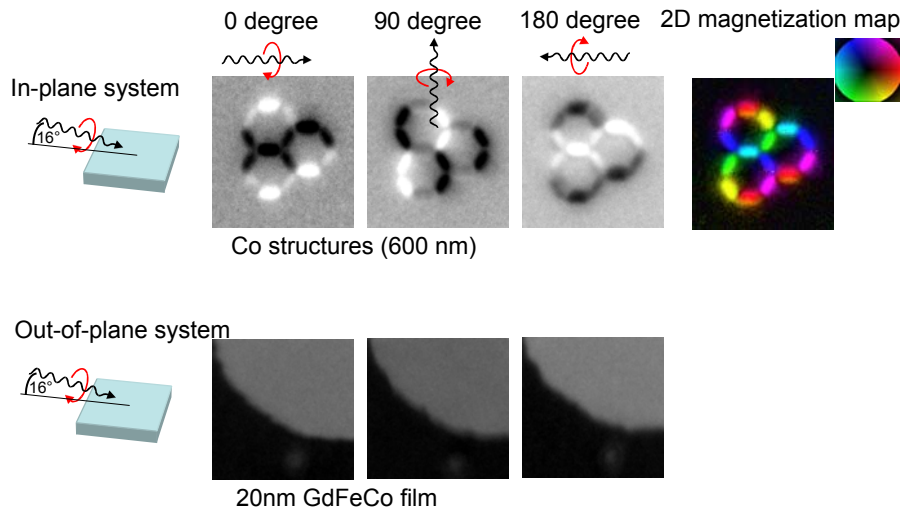


X-ray Magnetic Circular Dichroism (XMCD)

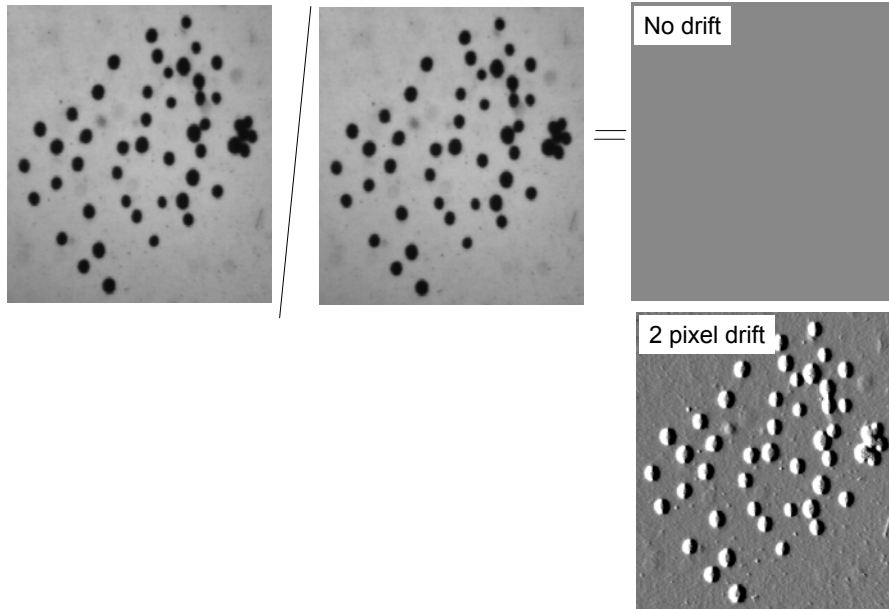


e.g. J. Stohr et al Surface Rev. Lett. 5, 1297 (1998).

X-ray Magnetic Circular Dichroism (XMCD)



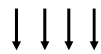
Be critical: Image drift!



Antiferromagnet

Ferromagnet (FM)

Net magnetic moment



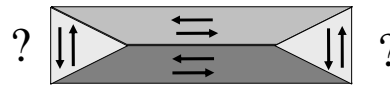
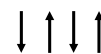
Magnetostatic energy

Exchange energy

Anisotropy energy

Antiferromagnet (AFM)

No net magnetic moment

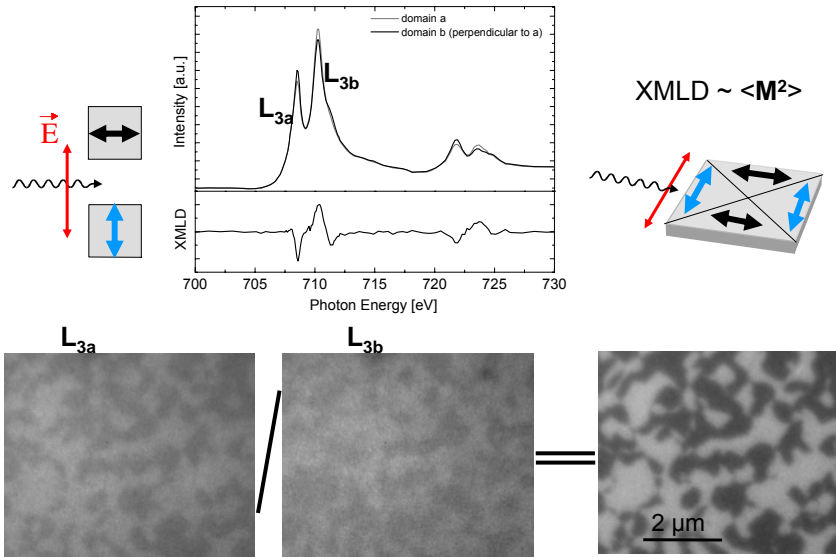


Exchange energy

Anisotropy energy

(magnetoelastic)

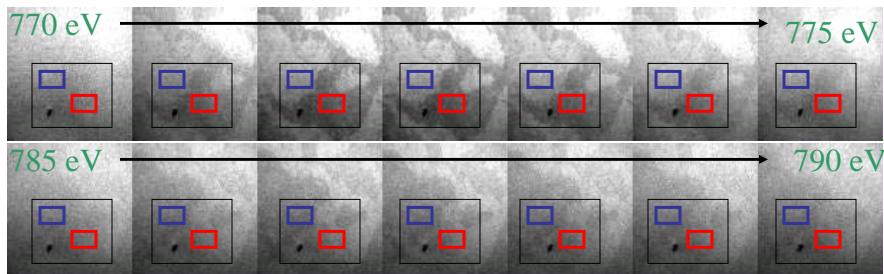
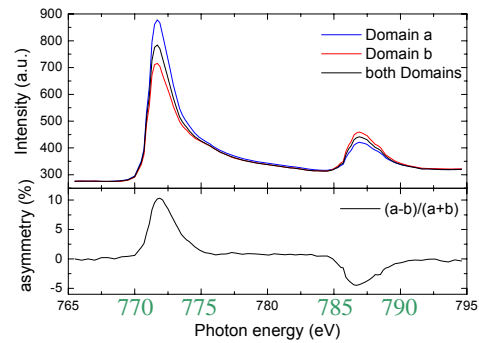
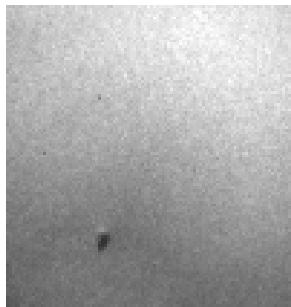
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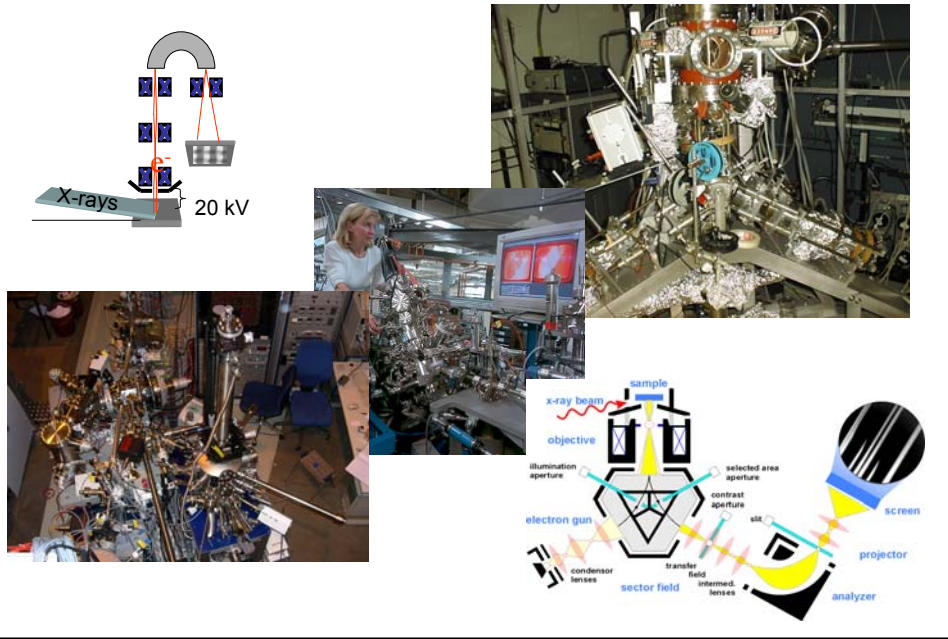
e.g. A. Scholl et al Science **287**, 1014 (2000)

PEEM : Local Spectra

5 μm



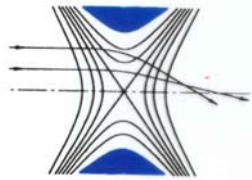
Instrument of course more complex



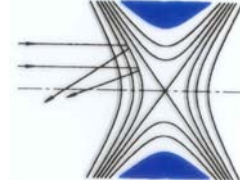
Aberrations and their correction

Spherical aberrations

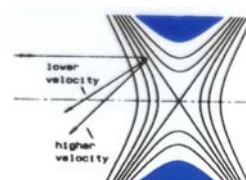
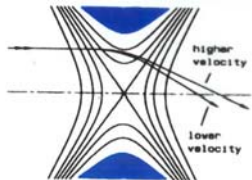
Lens

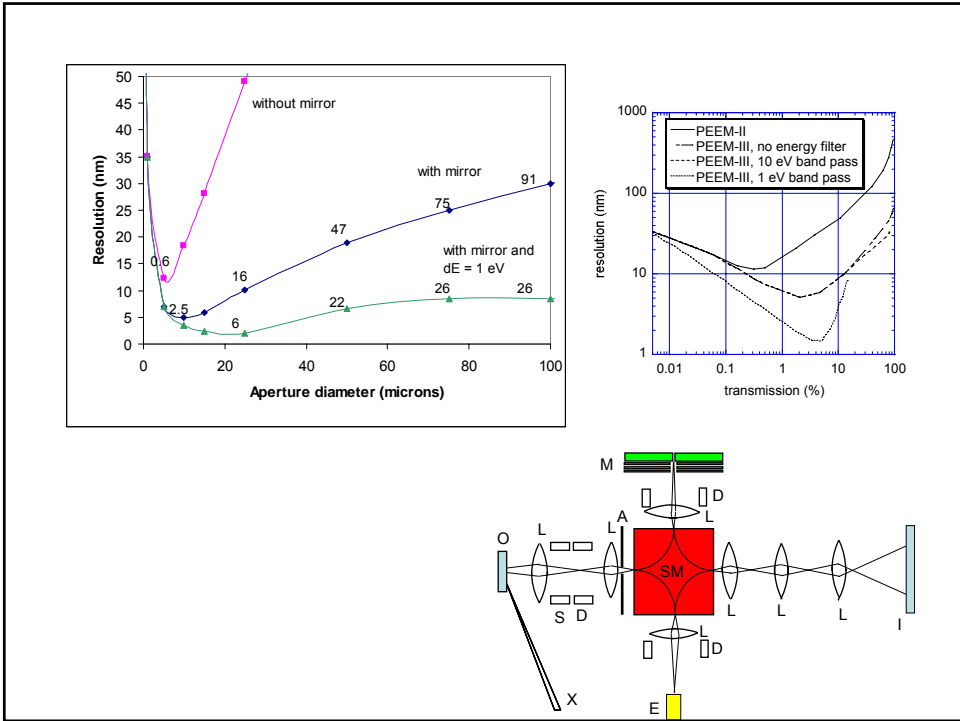


Mirror



Chromatic aberrations





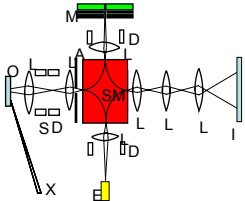
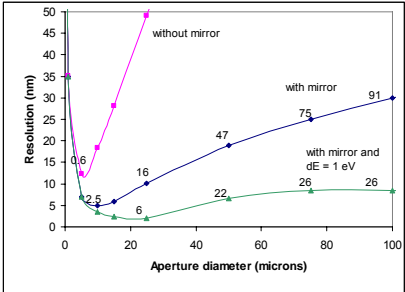
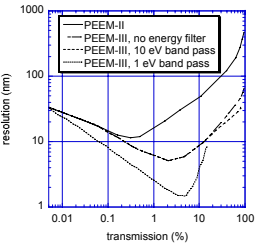
Aberration-corrected instruments



SMART (SpectroMicroscope for All Relevant Techniques)
 at BESSY II, Berlin, Germany
 collaboration of seven Universities in Germany
 status: LEEM 3 nm, X-PEEM about 20 nm

PEEM III
 at ALS, Berkeley, USA
 aberration corrected not yet build

Companies with aberration correction:
 ELMITEC
 SPECS



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Size-dependent spin structures in iron nanoparticles

A. Fraile Rodríguez¹, A. Kleibert¹, J. Bansmann², A. Voitekans², L. J. Heyderman¹,
and F. Nolting¹

¹Paul Scherrer Institut, Villigen PSI, CH-5232 Switzerland.

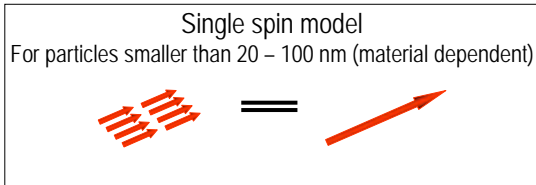
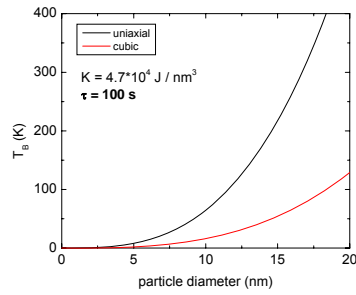
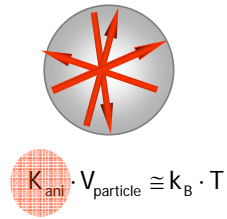
²Institute of Surface Chemistry and Catalysis, University of Ulm, D-89069 Ulm,
Germany.

³Institute of Physics, University of Rostock, D-18051 Rostock, Germany.

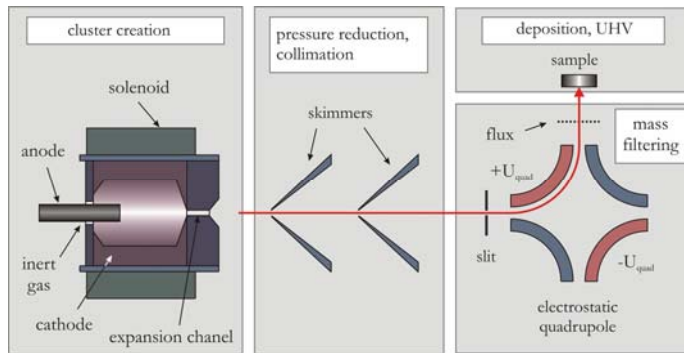
Spectroscopy of individual nanoclusters



Superparamagnetism

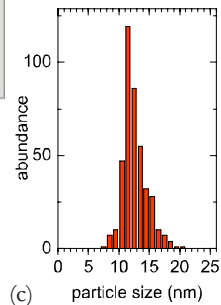


Mass-filtered nanoparticles: Arc-ion source



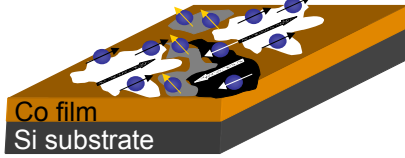
R. P. Methling et al.,
EPJD 16, 173 (2001)

- particle size tunable between 4-15nm
- size distribution: $\Delta D/D \sim 10\text{-}15\%$
- *in situ* deposition
- transportable and UHV compatible



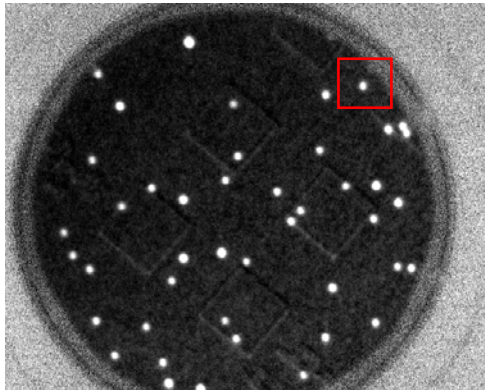
In-situ Fe particles deposited on cobalt surfaces

Fe particles (5-25 nm)

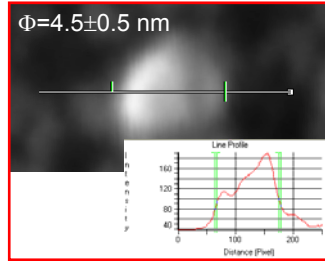


1. e-beam evaporation of cobalt thin films (2- 4 nm thickness)
2. in-situ deposition of Fe particles using arc-ion cluster source

Fe Elemental



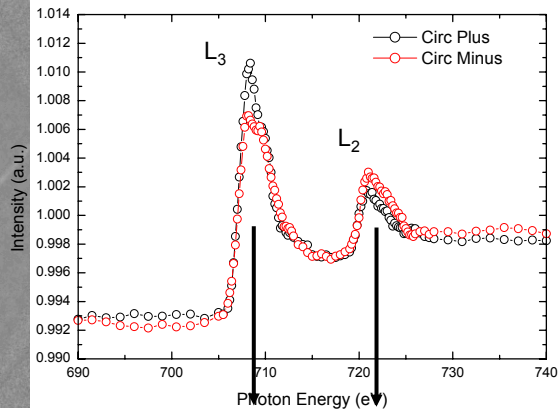
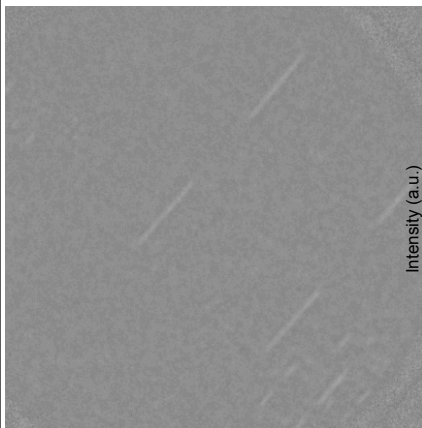
SEM



FOV = 20 micrometer

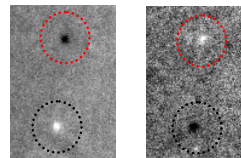
XMCD spectra of individual Fe nanoparticles

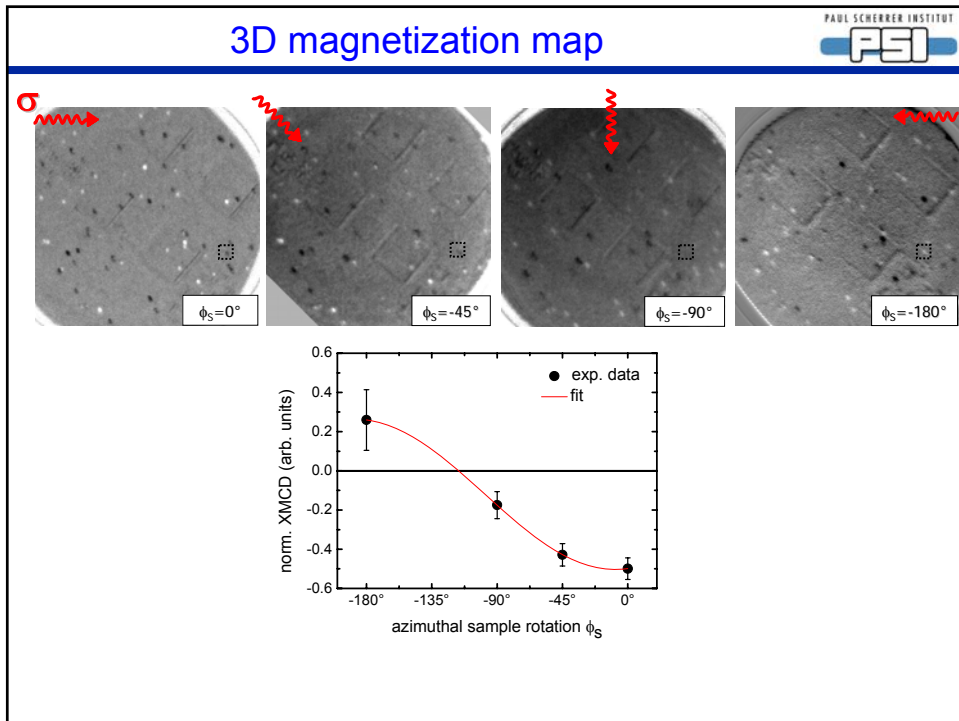
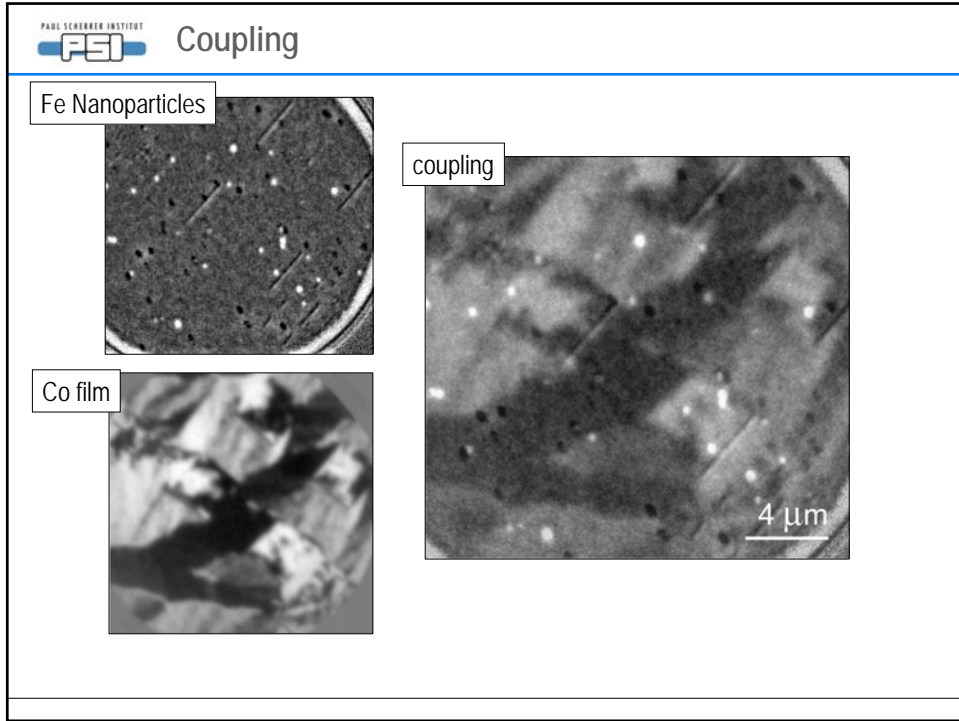
Sample: Fe nanoparticles with diameter = 9 nm

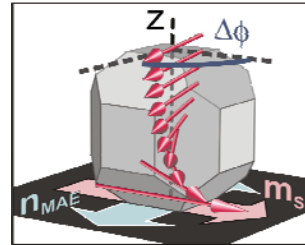
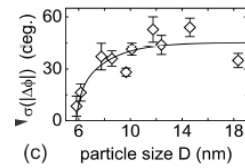
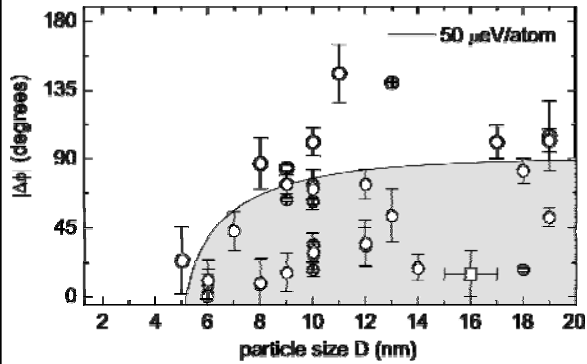


Images with increasing Photon Energy

XMCD image







Already for particles larger than 6 nm is the single-spin model not correct anymore

A. Fraile Rodríguez, A. Kleibert, J. Bansmann, A. Voitkans, L. J. Heyderman, and F. Nolting PRL 2010, in press

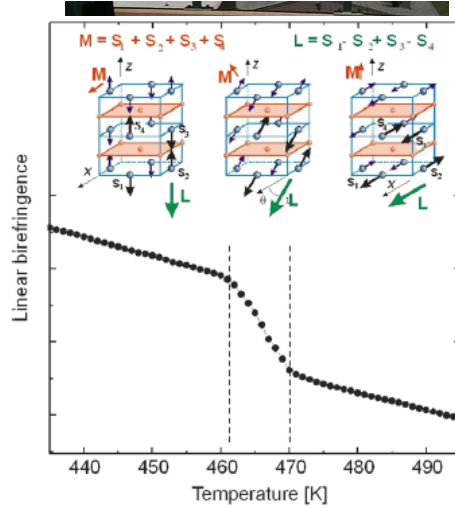
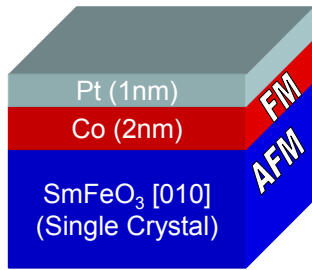
Spin reorientation in a coupled Antiferromagnetic/Ferromagnetic system

L. Joly, L. Le Guyader, A. Kleibert, and F. Nolting
SLS, Paul Scherrer Institut, Switzerland

A. V. Kimel, A. Kirilyuk, and Th. Rasing
IMM, Radboud University Nijmegen, The Netherlands

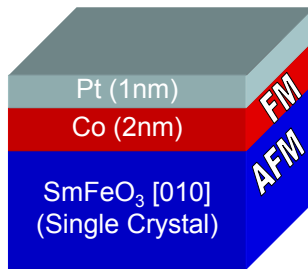
R. V. Pisarev
Ioffe Physical Technical Institute, St. Petersburg, Russia

The dynamics in an antiferromagnet can be faster than in a ferromagnet



L. Le Guyader, L. Joly, A. Kleibert, F. Nolting, R. Pisarev, A. Kirilyuk, Th. Rasing, A. Kimmel

“Exchange Bias”

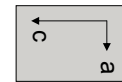


➤ coupling between the domains of the Co and SmFeO₃

➤ SmFeO₃ : Spin-reorientation phase transition at about 420 – 460 K
T_N = 675 K

Below spin reorientation temperature

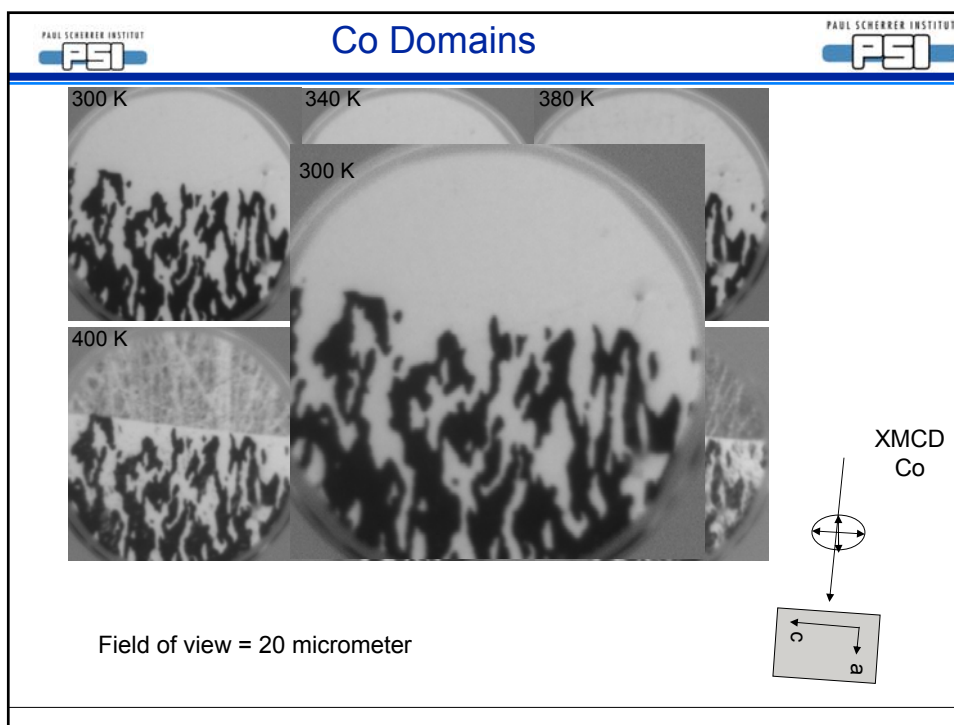
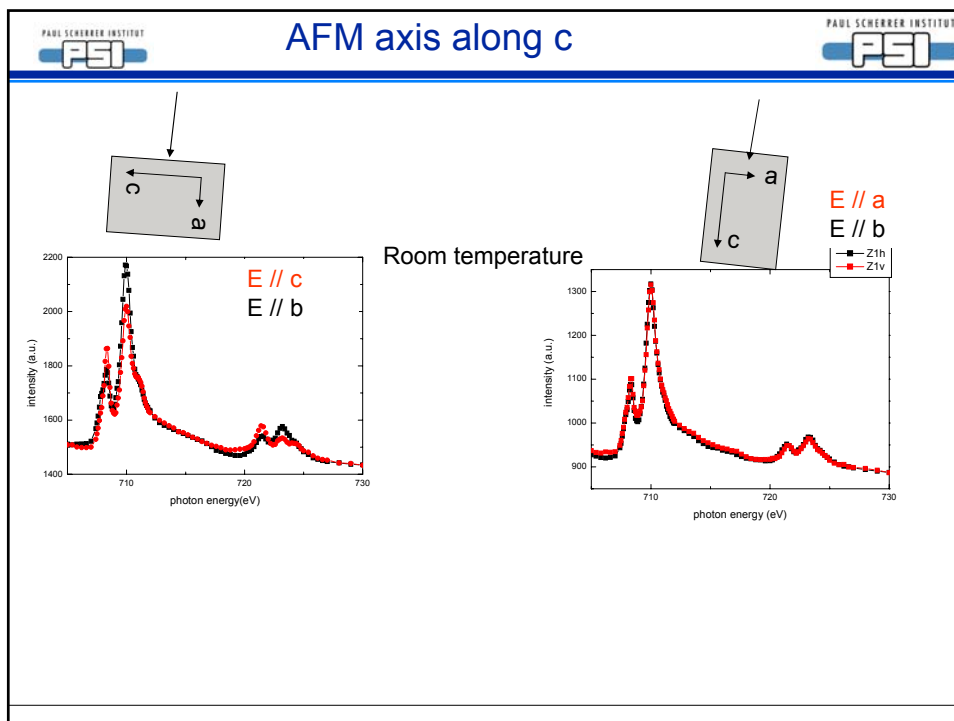
AFM axis parallel to c
weak ferromagnet parallel to a

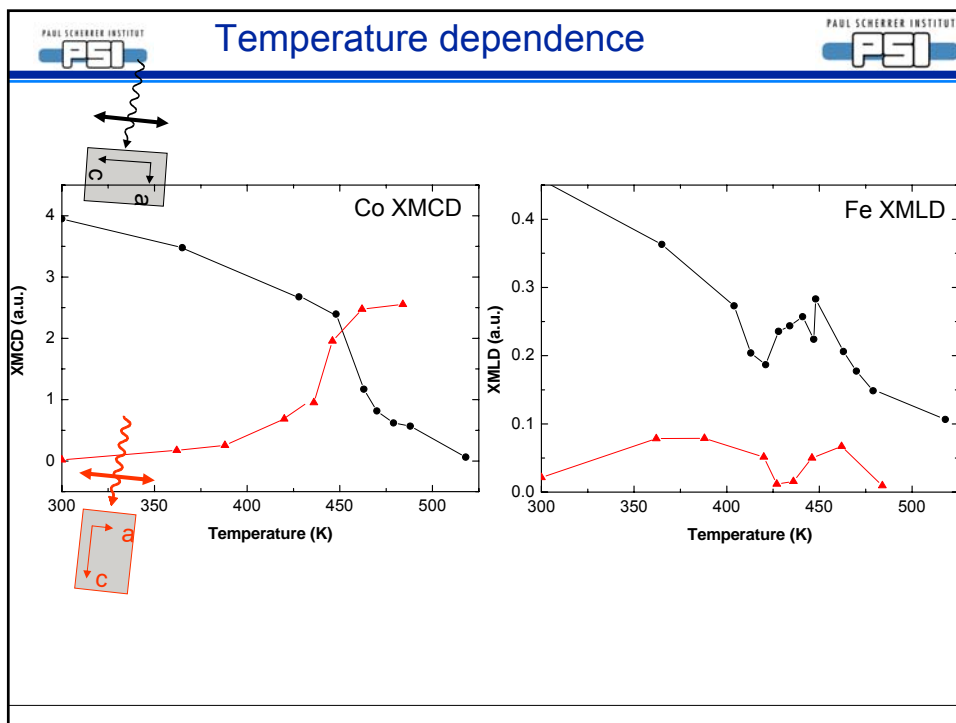
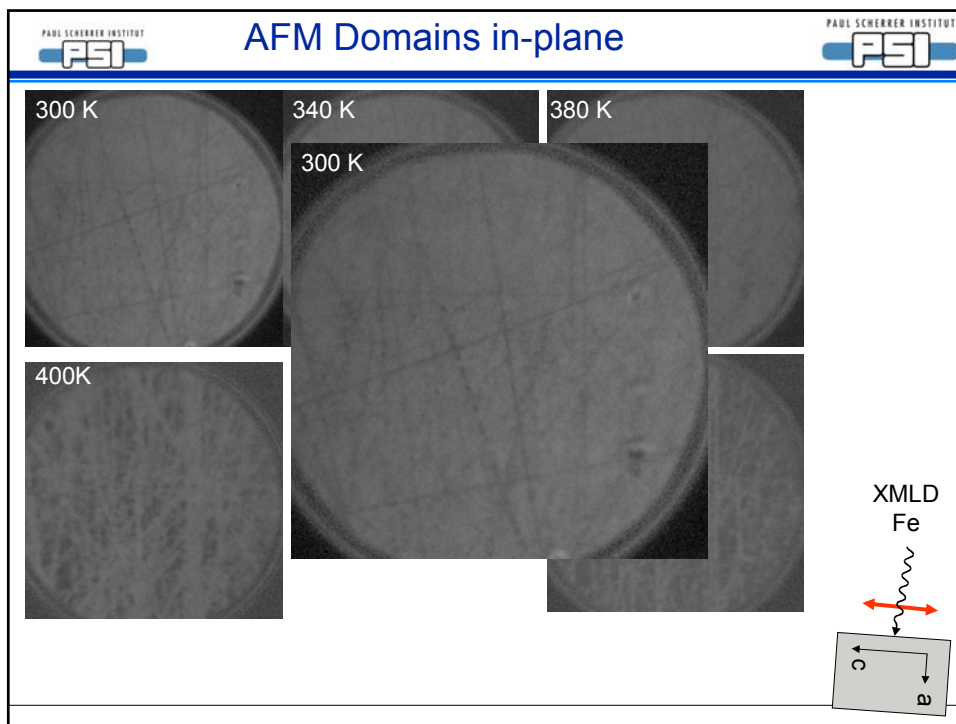


Above spin reorientation temperature

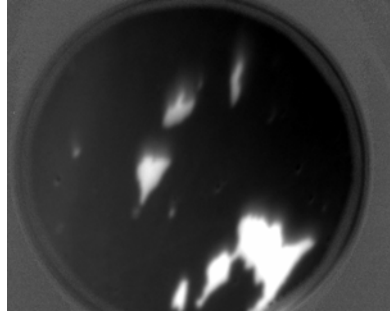
AFM axis parallel to a
weak ferromagnet parallel to c



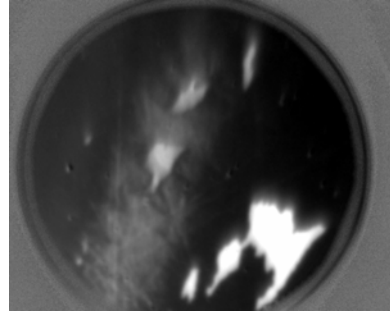




Co XMCD



Laser off



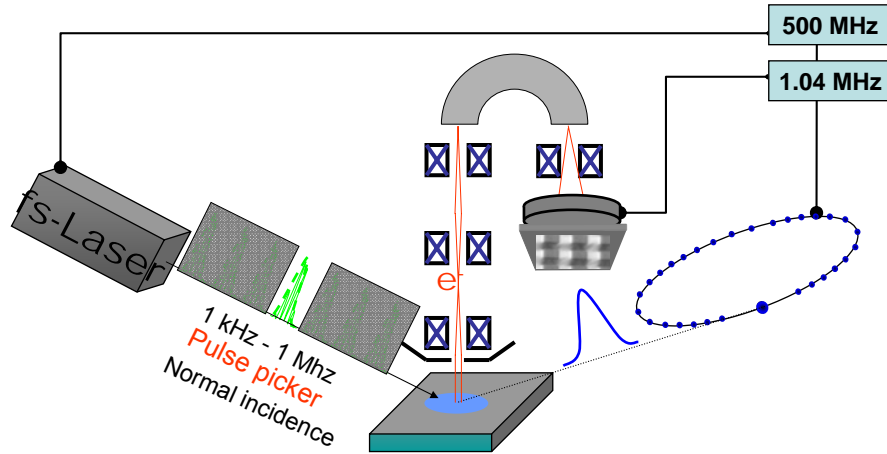
Laser on

L. Joly, F. Nolting, A. Kimel, A. Kirilyuk, Th. Rasing, R.V. Pisarev,
J. Phys.: Condens. Matter **21**, 446004 (2009).

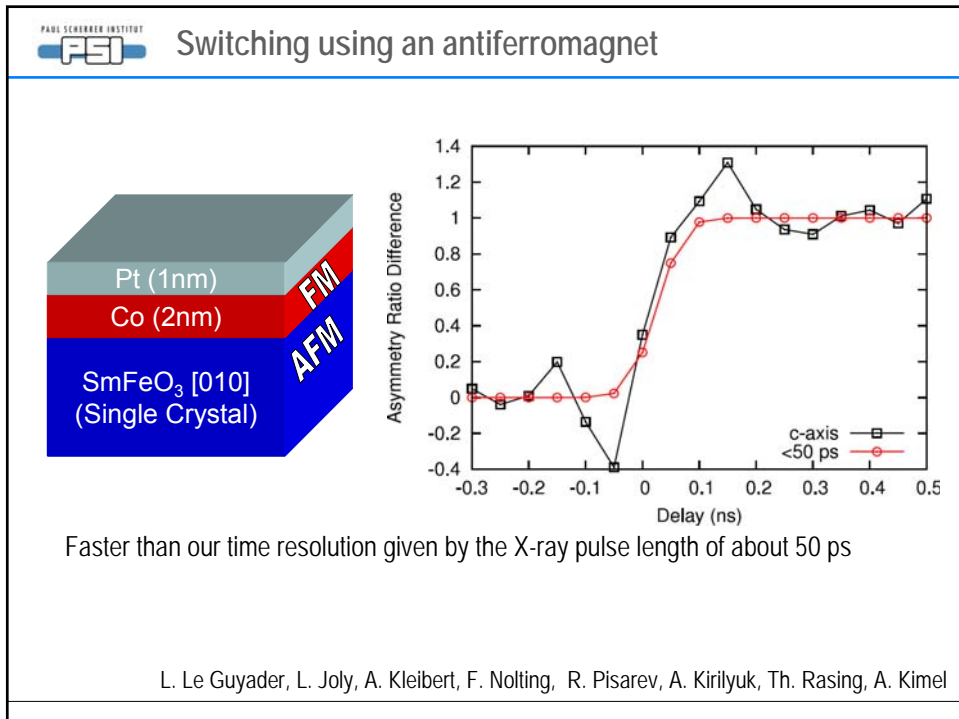
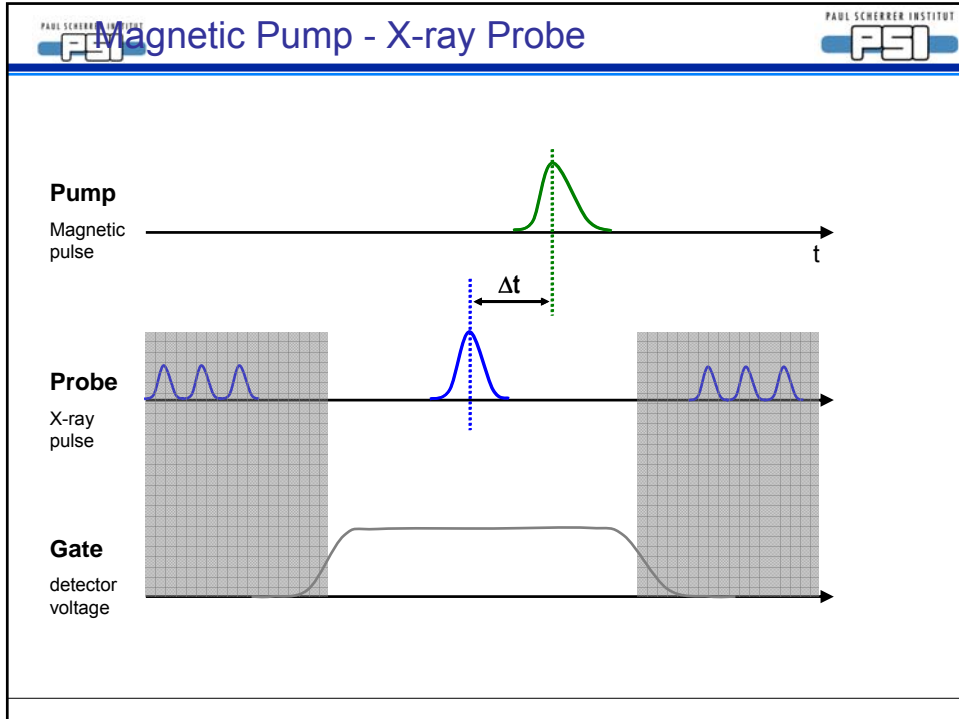
Pump:
Pulse: 50 fs

Detect:
gated PEEM
Dx ~100nm, ~ 1 ML

Probe:
X-ray stroboscope
~1keV, Δt= 70ps



Femtosource, scientific XL 500
50fs, 500nJ, 5.2 MHz, 800 nm

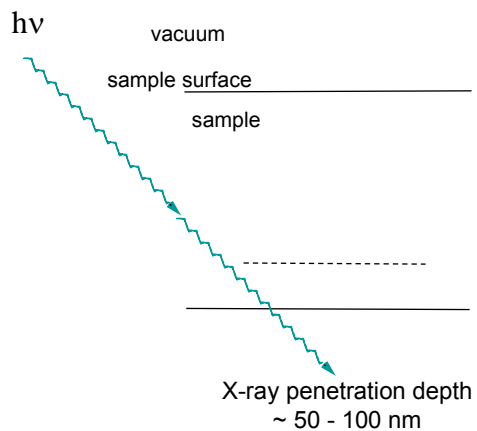


- Repetition Spectroscopy
- Crash course nanomagnetism
- Photoemission electron microscope (PEEM)
 - Technique
 - Nanocrystals
 - Heterostructure/Magnetisation dynamics
- Transmission X-ray microscope (Scanning: STXM/ full field: TXM)
- Combine X-rays with scanning probe microscopy
- PEEM without X-rays

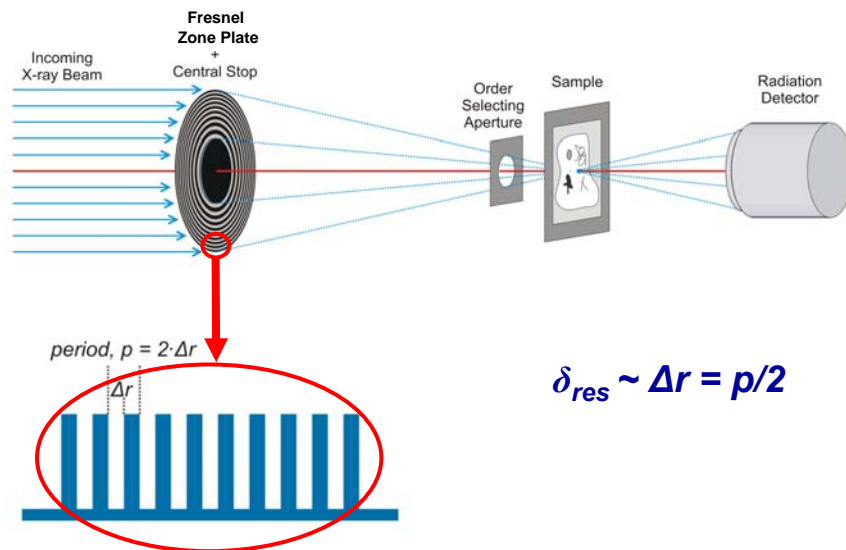
Photon in / Photon out

Photon in / Photon out

You need an optic for the
(incoming) photons

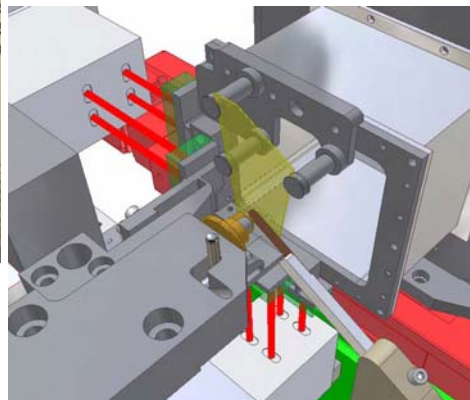
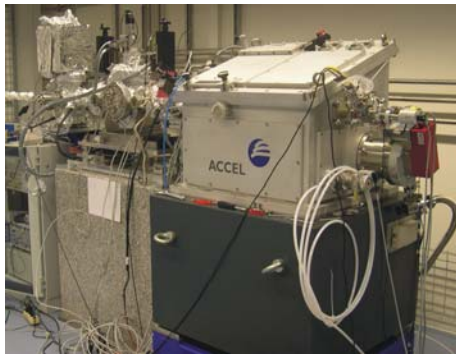


Spatial Resolution in X-ray Microscopy

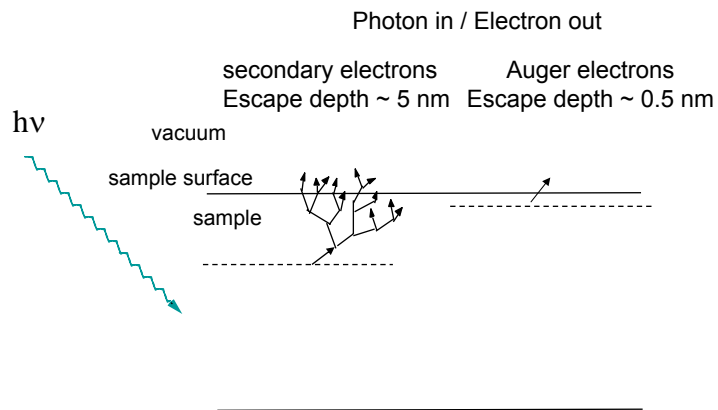


Courtesy J. Vila-Comamala (PSI)

STXM at the PoLux beamline at the SLS



Back to Photon in / Electron out but ...



Combine scanning probe microscopy with X-ray absorption spectroscopy

NanoXAS project at SLS

I. Schmid^{1,2}, J. Raabe¹, C. Quitmann¹, S. Vranjkovic², H. J. Hug²
and R. H. Fink³

Endstation:

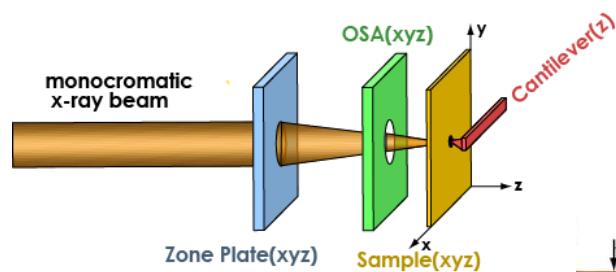
¹PSI, Swiss Light Source, 3252 Villigen

²EMPA, Nanoscale Materials Science, 8600 Dübendorf

Beamline:

³Universität Erlangen-Nürnberg, 91058 Erlangen, Germany

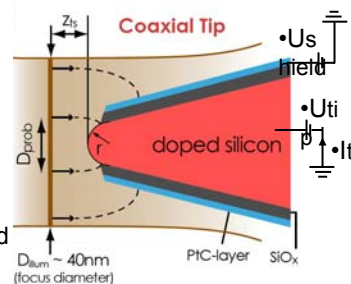
NanoXAS project at SLS



The NanoXAS instrument contains:

- Scanning Transmission X-ray Microscope (STXM) – chemical analysis
- Scanning Force Microscope (SFM) and in principle STM – sample topography
- Combination: STXM & SFM - chemical sensitivity and high spatial resolution.

Cantilever Tip acts as a local photoelectron detector!



Very brief comparison to other techniques

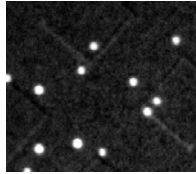
Table 2. Summary of the features of the discussed magnetic imaging techniques. Columns with pictograms refer (from left to right) to resolution, image acquisition speed, type of imaging (parallel imaging or scanning), sensitivity to applied magnetic fields, type of depth information (surface based or transmission), information depth (path length for exponential weighting for surface based techniques, maximum sample thickness for transmission techniques), possibility to obtain depth selective information

Kerr microscopy						< 20 nm	
Lorentz microscopy						< 100 nm	
SEMPA						< 0.5 nm	
SPLEEM						< 1 nm	
XMCD-PEEM						< 5 nm	
M-TXM						< 200 nm	
MFM						< 2 μm	
sp-STM						< 0.2 nm	

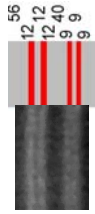
"correction" F. Nolting

Spatial resolution?

4 nm Fe particles
PEEM

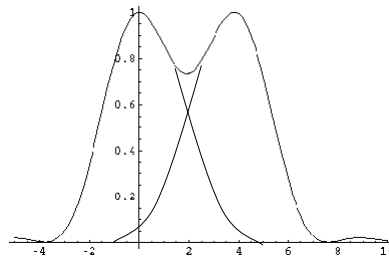


What is the spatial resolution?

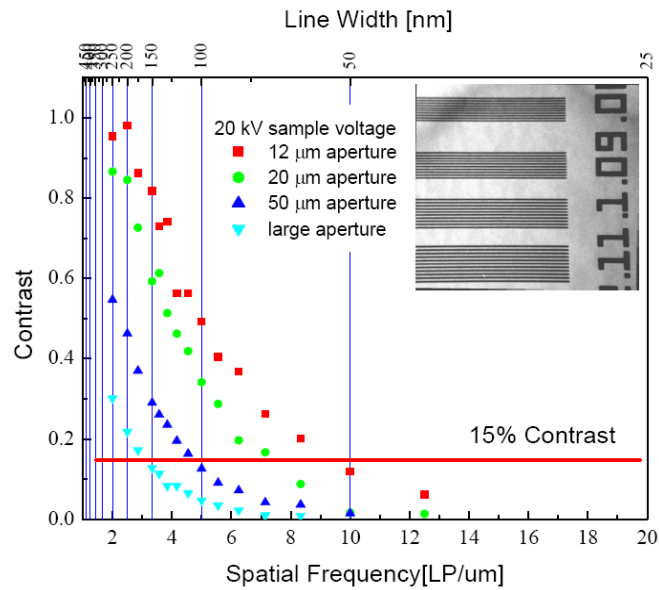


Is this contrast good enough to identify unknown, not periodic structures?

Which spatial resolution you need for spectroscopy?



Spatial resolution?



Courtesy Andreas Scholl (ALS)

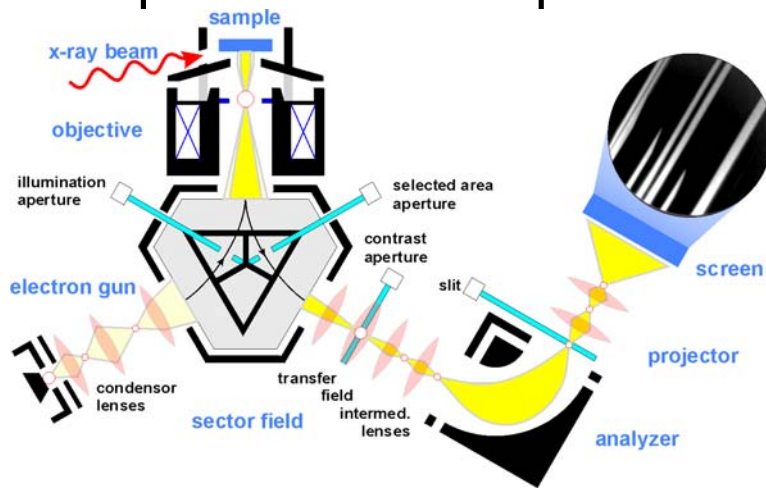
Outline

- Repetition Spectroscopy
- Crash course nanomagnetism
- Photoemission electron microscope (PEEM)
 - Technique
 - Nanocrystals
 - Heterostructure/Magnetisation dynamics
- Transmission X-ray microscope (Scanning: STXM/ full field: TXM)
- Combine X-rays with scanning probe microscopy
- PEEM without X-rays

Not only with X-rays

- PEEM with UV light
 - 10 nm spatial resolution
 - workfunction and topography contrast
- PEEM with slow electrons
 - 8 nm spatial resolution
 - LEED, LEEM, MEM
- PEEM with X-rays
 - 50-20 nm spatial resolution
 - spectromicroscopy

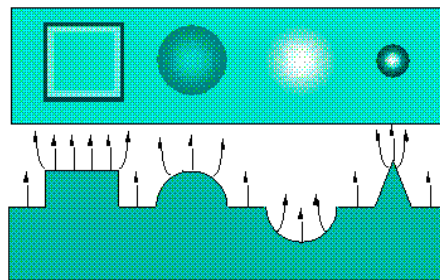
Spectromicroscope



L.H. Veneklasen: Ultramicroscopy 36 (1991), 76
Image courtesy of S. Heun (ELETTRA)

Elmitec Elektronenmikroskopie GmbH
Clausthal-Zellerfeld, Germany

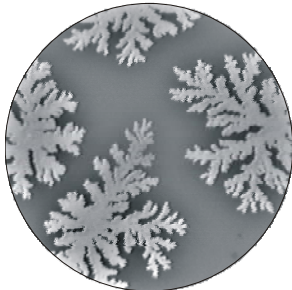
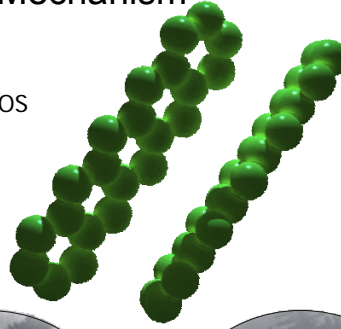
Topographical Contrast



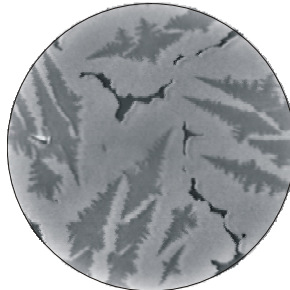
Distortion of the electric field due to topography

PEEM Contrast Mechanism

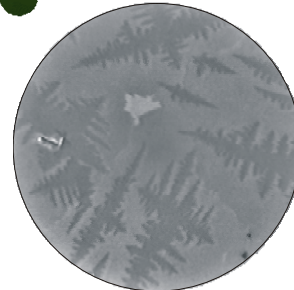
- Mercury lamp (5eV)
- Contrast either by Work Function or DOS
- Pentacene: 5 Benzene Rings
- Contrast Changes During Deposition
- FoV = 65 μm



1 Layer



2 Layers



3 Layers

F.-J. Meyer zu Heringdorf et al., NATURE 412 (517), 2001

Source: slow electrons

How slow electrons interact with matter

Fast electron



40 eV



20 eV



Elastic backscattering

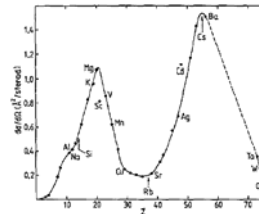
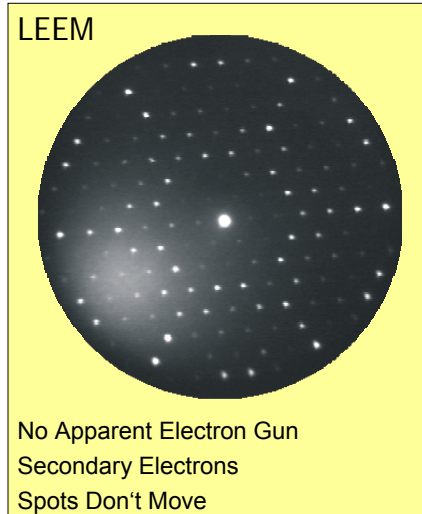
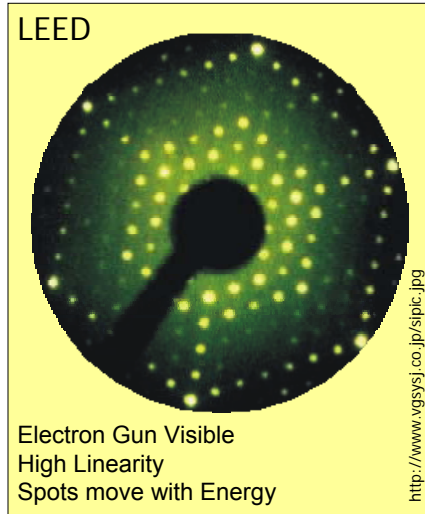
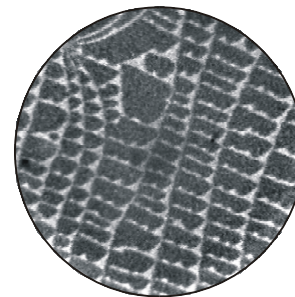
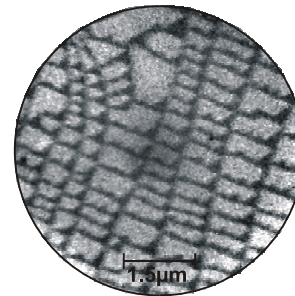
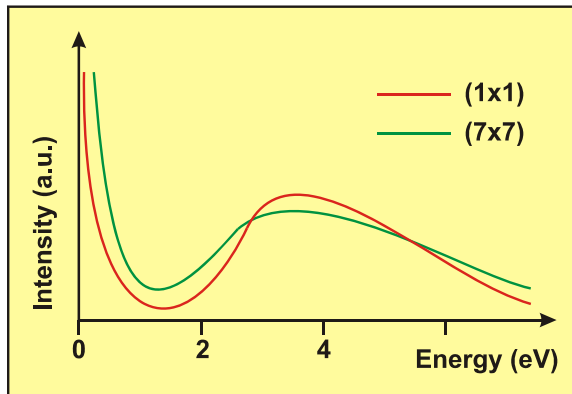


Figure 2. Elastic backscattering cross sections $\sigma_{\text{elastic}} / \sigma_T$ of free atoms as a function of nuclear charge Z for 100 eV electrons. The dashed line is a simple interpolation.

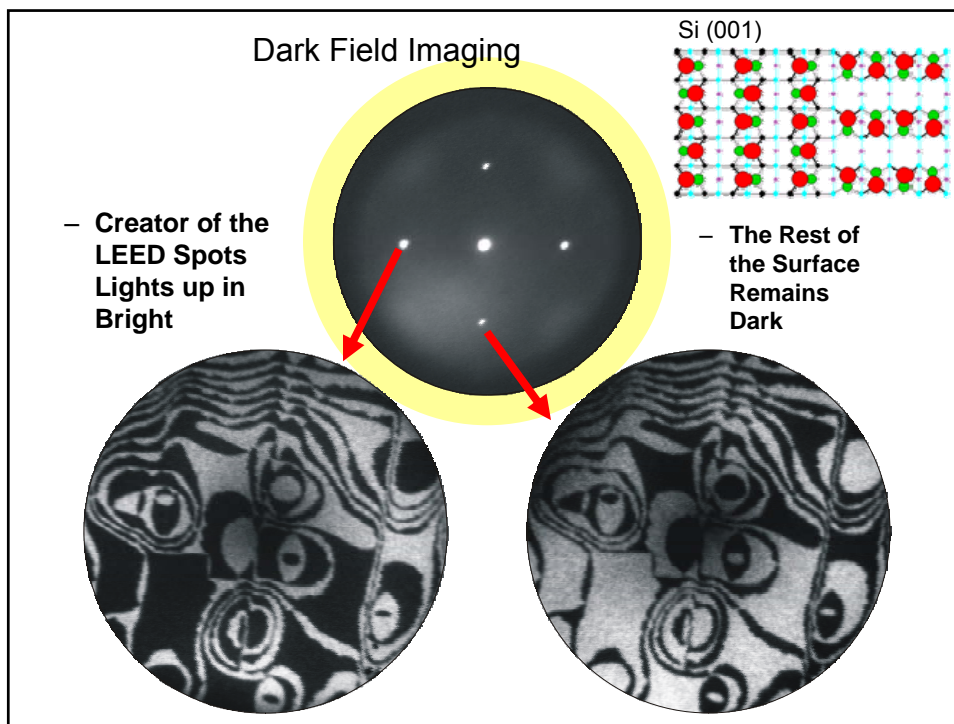
Low Energy Electron Diffraction



Bright Field Imaging of Si (111)



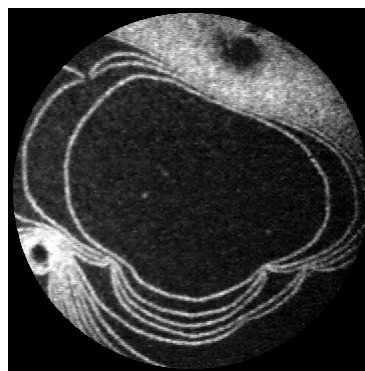
- Different Reflectivity of (1x1) and (7x7)
- Reflectivity Energy Dependent
- Contrast Reversal Dependent on Imaging Conditions



**Direct Observations of Nanoscale Self-Assembly and
Pattern Formation Solid Surfaces**

by R. Plass, N. C. Bartelt, and G. L. Kellogg

LEEM-Movie of the growth of Pb on a Cu(111) surface.



Nature, 412 (2001) 875

Three-dimensional magnetic-flux-closure patterns in mesoscopic Fe islands

R. Hertel,^{1,*} O. Fruchart,² S. Cherifi,² P.-O. Jubert,³ S. Heun,⁴ A. Locatelli,⁵ and J. Kirschner⁶

¹Institute of Solid State Research (IFF), Research Center Jülich, D-52425 Jülich, Germany

²Laboratoire Louis Néel, CNRS-UJF-INPG, BP166, F-38042 Grenoble Cedex 9, France

³IBM Research, Zurich Research Laboratory, CH-8803 Rüschlikon, Switzerland

⁴TASC-INFM Laboratory, Area di Ricerca, Basovizza, I-34012 Trieste (TS), Italy

⁵Sincrotrone ELETTRA, I-34012 Basovizza, Trieste, Italy

⁶Max-Planck Institute of Microstructure Physics, Weinberg 2, 06120 Halle, Germany

(Received 23 June 2005; revised manuscript received 6 September 2005; published 6 December 2005)

We have investigated three-dimensional magnetization structures in numerous mesoscopic Fe/Mo(110) islands by means of x-ray magnetic circular dichroism combined with photoemission electron microscopy (XMCD-PEEM). The particles are epitaxial islands with an elongated hexagonal shape with length of up to $2.5 \mu\text{m}$ and thickness of up to 250 nm. The XMCD-PEEM studies reveal asymmetric magnetization distributions at the surface of these particles. Micromagnetic simulations are in excellent agreement with the observed magnetic structures and provide information on the internal structure of the magnetization which is not accessible in the experiment. It is shown that the magnetization is influenced mostly by the particle size and thickness rather than by the details of its shape. Hence these hexagonal samples can be regarded as model systems for the study of the magnetization in thick, mesoscopic ferromagnets.

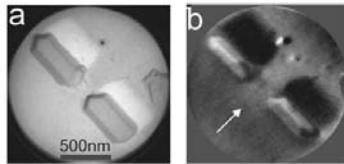
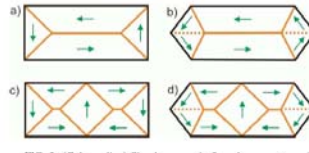


FIG. 2. Example of an experimental observation of the particle shape and the magnetization structure. (a) Two Fe islands, incidentally located next to each other, imaged with LEEM. (b) The XMCD-PEEM image displays the in-plane magnetization component parallel to the incident beam. The beam direction is sketched by the white arrow. Due to grazing incidence of the photons (74° with respect to the plane normal) the back side of the island is shadowed; thus it appears dark in the XMCD-PEEM image.

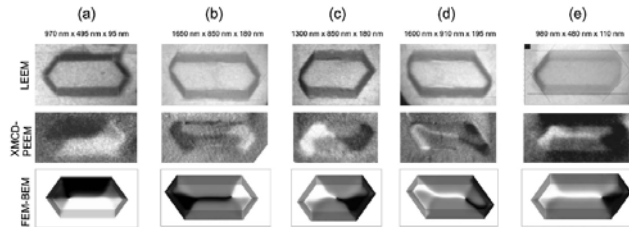
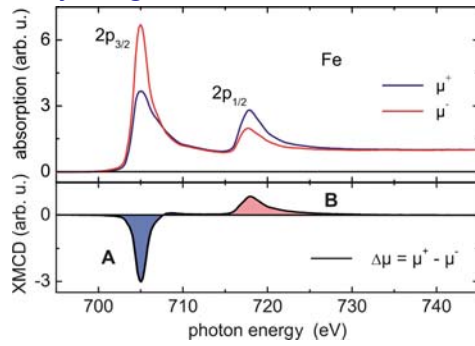
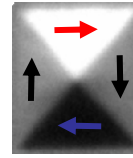


FIG. 6. Experimental and simulated data for five self-assembled Fe/Mo(110) islands of different size and shape (a)–(e). *First row:* The shape of the particle is obtained by LEEM imaging. The particle thickness is derived from the width of the (001) facets, which appear as a dark border around the hexagonal top surface, by using the known inclination angles of the inclined facets (cf. Fig. 1). The sample's approximate lateral dimension and thickness is displayed on top of each column. *Second row:* One magnetization component in the surface plane is imaged as grey scale with XMCD-PEEM. In sample (a), the contrast refers to the magnetization component parallel to the long edge while in the other samples the in-plane magnetization component perpendicular to the long edge is displayed. Notice that only the top surface, i.e., the light grey internal hexagon in the first row, is imaged. *Third row:* Micromagnetic simulation results. To compare the results with the XMCD-PEEM experiments, the same magnetization component is displayed in grey scale. The sample shape was modeled according to the LEEM images and the model explained in Fig. 1.

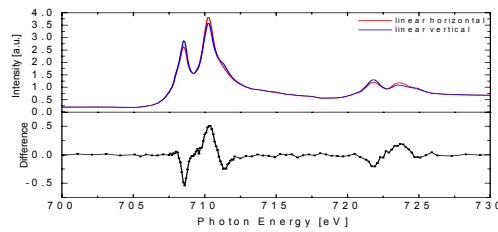
X-ray Magnetic Circular Dichroism (XMCD)



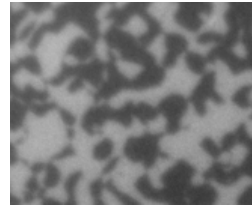
$$\text{XMCD} \sim \mathbf{M} \cos(\mathbf{M}, \mathbf{S})$$



X-ray Magnetic Linear Dichroism (XMLD)



$$\text{XMLD} \sim \langle M^2 \rangle$$



Photoemission Electron Microscopy using X-Rays

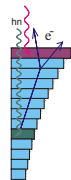
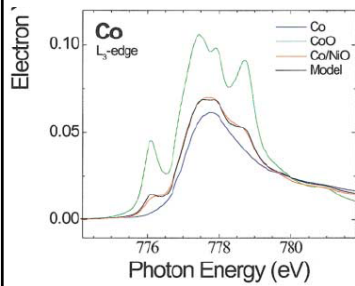
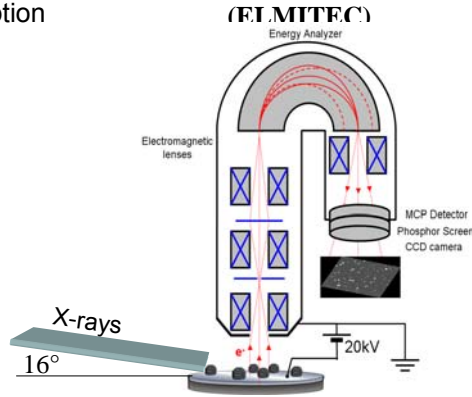


Schematic layout of the PEEM (EIMTEC)

Spatially resolved X-ray absorption spectroscopy

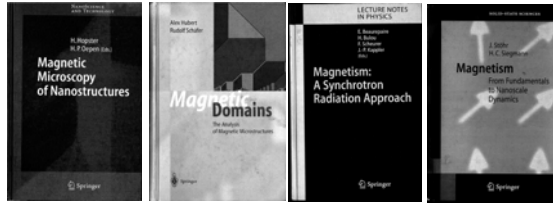
Sensitive to:

- elemental composition
- chemical bonds
- structural parameters
- electronic structure
- magnetic properties



Probing surface/interface

Some good books/ reviews



Magnetic imaging,
F U Hillebrecht, J. Phys.: Condens. Matter 13, 11163 (2001)

Photoelectron microscopy and applications in surface and materials science,
S. Günther, B. Kaulich, L. Gregoratti, M. Kiskinova, Progress in Surface Science 70, 187 (2002)

Recent advances in chemical and magnetic imaging of surfaces and interfaces by XPEEM,
A Locatelli and E Bauer J. Phys.: Condens. Matter 20, 093002 (2008)

Principles of X-ray magnetic dichroism spectromicroscopy,
J. Stöhr, S. Anders, T. Stammli, and M.R. Scheinfein, Surface Review and Letters, 5, 1297 (1998)

Brief History PEEM

1930s	<p>Electron lenses/electron microscopy Photoemission electron microscope (PEEM) E. Brueche, Z. Phys. (1933) 448 Low Energy Electron Diffraction (LEED) W. Ehrenberg, Philos. Mag. 18 (1934) 878</p>	<p>Reviews (X-PEEM) J. Stöhr et al., Surf. Rev. Lett. 6 (1998) 1297 E. Bauer, J. Phys.: Condens Matter 13 (2001) 11391 Th Schmidt et al., Surf. Rev. Lett. 9 (2002) 223</p>
1960s	<p>improved LEED E.J. Scheibner, L.H. Germer and C.D. Hartman, Rev. Sci. Instrum. 31 (1960) 112 Invention of Low energy electron microscop (LEEM) by Ernst Bauer Glass-Based Vacuum Apparatus (1962)</p>	
1985	<p>First Operational LEEM Instrument Telieps and Bauer, Ultramicroscopy 17 (1985) 57</p>	
1991	<p>IBM LEEM-I Tromp and Reuter</p>	
Since 1990	<p>several groups and companies: Elmitec LEEM (Former Coworkers of E. Bauer) Staub, Omicron Schoenhense, Kirschner De Stasio</p>	
	<p>Synchrotron based PEEM pioneering G. Harp and B. Tonner, Rev. Sci. Instrum. 59 (1988) 853 Magnetism: Stöhr et al, Science 259 (1993) 658</p>	
Since 2000	<p>world wide several beamlines for PEEM</p>	
Future	<p>Aberration-corrected instruments (SMART / Germany, PEEMIII / USA) spatial resolution ~ nm</p>	